

# SPIRE

**SUBJECT: SPIRE Instrument Development Plan**

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## 1. INTRODUCTION

### 1.1 Purpose

The purpose of this document is to describe the development of the deliverable models of the FIRST SPIRE instrument, including their assembly, integration and test. It also includes the provision of the test equipment, test facilities and simulators necessary for this development.

This document is an applicable document to the subsystems development plans, which are to be written by the SPIRE Responsible Organisations (ROs) who will implement each subsystem (RD1 - RD14).

### 1.2 Scope

This document covers the development of the SPIRE instrument hardware and its on-board software and the additional equipment required for its assembly, integration and test. The development of the SPIRE contribution to the FIRST Ground Segment (the Instrument Control Centre) is described in the SPIRE Science Implementation Plan (RD15).

The development activities that contribute to the provision of the instrument models take place at many different centres, both at ROs and in industry. Those activities contributing to the development of subsystems are detailed in the individual subsystems development plans (RD1-RD14). This plan concentrates only on the deliveries made between ROs and those deliveries made to RAL for final integration into the instrument.

### 1.3 Glossary

DDR	Detailed Design Review
DPU	Digital Processing Unit
DRCU	Detector Readout and Control Unit
FIRST	Far Infrared and Submillimetre Telescope
FPU	Focal Plane Unit
IIR	Instrument Interface Review
PDR	Preliminary Design Review
RO	Responsible Organisation
SPIRE	Spectral and Photometric Imaging REceiver
WIH	Warm Interconnect Harness

### 1.4 References

#### 1.4.1 Applicable Documents

Document Reference	Name	Number/version/date
AD1	FIRST/Planck Instrument Interface Document Part A	SPIRE-ESA-DOC-000178

	(IID-A)	(PT-IID-A-04624) Issue 0-3 15 May 2000
AD2	FIREST/Planck Instrument Interface Document Part B (IID-B) Instrument "SPIRE"	SPIRE-ESA-DOC-000275 (PT-SPIRE-02124) Issue 0-4 15 May 2000
AD3	SPIRE Management Plan	FIRST-SPI-PRJ-000011 (SPIRE-RAL-PRJ-000029) Issue 1.0 22 <sup>nd</sup> June 1999

#### 1.4.2 Reference Documents

Document Reference	Name	Number/version/date
RD1	SPIRE Structure Development Plan	SPIRE-MSS-PRJ-000426 Issue 1.0 11 <sup>th</sup> June 2000
RD2	SPIRE Mirrors Development Plan	(LAM.PJT.SPI.NOT.200006) v0000601 13 <sup>th</sup> June 2000
RD3	SPIRE Filters Development Plan	Draft 1.0 6 <sup>th</sup> June 2000
RD4	SPIRE BSM Development Plan	Issue 1.0
RD5	SPIRE Cooler Development Plan	(PL/SBT/SPIRE/2000-01) Issue 1.1 May 2000
RD6	SPIRE Arrays Development Plan	TBW
RD7	SPIRE FET Box Development Plan	TBW
RD8	SPIRE Spectrometer Mirror Mechanism Development Plan	(LAM.PJT.SPI.NOT.200001) v0000105 6 <sup>th</sup> June 2000
RD9	SPIRE Calibrators Development Plan	Draft 1.0 6 <sup>th</sup> June 2000
RD10	SPIRE Shutter Development Plan	(SPIRE-USK-DOC-000001) Draft 0.2 15 <sup>th</sup> June 2000
RD11	SPIRE DPU Development Plan	(F-13.06.00) Issue 1 13 <sup>th</sup> June 2000
RD12	SPIRE DRCU & WIH Development Plan	(SAp-SPIRE-JLA-xxxx-00) Issue 1.0 6 <sup>th</sup> June 2000
RD13	SPIRE DRCU Simulator Development Plan	Draft 4 <sup>th</sup> May 2000
RD14	SPIRE Test Facility Development Plan	Draft 1.0 19 <sup>th</sup> June 2000
RD15	SPIRE Science Implementation Plan (SIP)	
RD16	SPIRE Optical System Design Description	Draft

		25 <sup>th</sup> May 2000
RD17	SPIRE Straylight Model Update	Draft 14 <sup>th</sup> June 2000
RD18	SPIRE Optical Design - diffraction analysis and design	Issue 1.0 14 <sup>th</sup> June 2000
RD19	SPIRE Optical Error Budgets	(LOOM.KD.SPIRE.2000.002) Draft 22 <sup>nd</sup> May 2000
RD20	SPIRE AOV Plan	SPIRE-RAL-DOC-000410 Issue 01. 25 <sup>th</sup> May 2000

## 1.5 Document Overview

Chapter 2 describes the development of the instrument in terms of the ESA schedule and deliverable instrument models required in the Instrument Interface Document Part A (AD1) and the SPIRE organisation described in the Instrument Interface Document (AD2) and the SPIRE Management Plan (AD3).

Chapter 3 describes aspects of the development of the instrument subsystems.

Chapter 4 describes the development plans for the test facilities, support equipment and simulators required for assembly, integration, test and calibration of the instrument at all levels.

Chapter 5 is devoted to the instrument Assembly, Integration and Test.



## 2. INSTRUMENT DEVELOPMENT

This document covers the development, manufacture and test of the different models of the SPIRE instrument. These activities require the development of three elements; the instrument itself; the Test Facility in which the instrument-level testing will take place and the simulators required to take the place of various instrument units during integration and testing.

### 2.1 Development Items

#### 2.1.1 The Instrument

A description of the SPIRE instrument and its capabilities is given in AD2. The instrument consists of 5 units;

- **Focal Plane Unit (FSFPU)** - this consists of all the subsystems contained within the FIRST cryostat, excluding the cold electronics (i.e. FET amplifiers).
- **FET Box (FSFTB)** -this contains the cold preamplifiers for the detector signals from the FSFPU. It is assembled with the FSFPU and they are then mounted on the optical bench as one unit.
- **Detector Readout and Control Unit (FSDRC)** - the electronics box external to the cryostat that houses the detector control and read out electronics; the mechanism control electronics, the subsystem housekeeping electronics and their power supply.
- **Digital Processing Unit (FSDPU)** - the instrument on board computer handling the command and telemetry interface to the spacecraft and the control of the operation of the instrument through the DRCU.
- **Warm Interconnect Harness (FSWIH)** - the harness connecting the DPU and DRCU.

All other harnesses; the cryoharness connecting the FPU and DRCU and the power, telemetry and telecommand harnesses are provided by ESA and do not form part of the instrument.

#### 2.1.2 Simulators

Additional deliverable items will be the support equipment necessary to install and verify the installation of Instrument Units. These additional items include:

- **FPU Simulator** - this item simulates the FPU as far as their interfaces with the DRCU are concerned. This will be delivered to ESA at the time of the CQM model delivery, to be used to aid integration of the warm electronics units of all models into the S/C.
- **DRCU Simulator** - this item simulates the cold FPU and the warm electronics in the DRCU. It forms part of the AVM, simulating the instrument response to commands from the spacecraft and generating simulated telemetry data.

**Figure 2-1** is a block diagram of the instrument showing the different units and the subsystems they contain. **Figure 2-2** shows the instrument broken down into its various deliverables.

#### 2.1.3 Test facility

This facility provides; a cryostat to simulate the thermal environment in which the instrument will operate; a telescope simulator and calibration sources to allow verification of the instrument specifications and its calibration; and EGSE to control and monitor the instrument and test equipment during the test and calibration activities. A description of the facility is given in RD14.

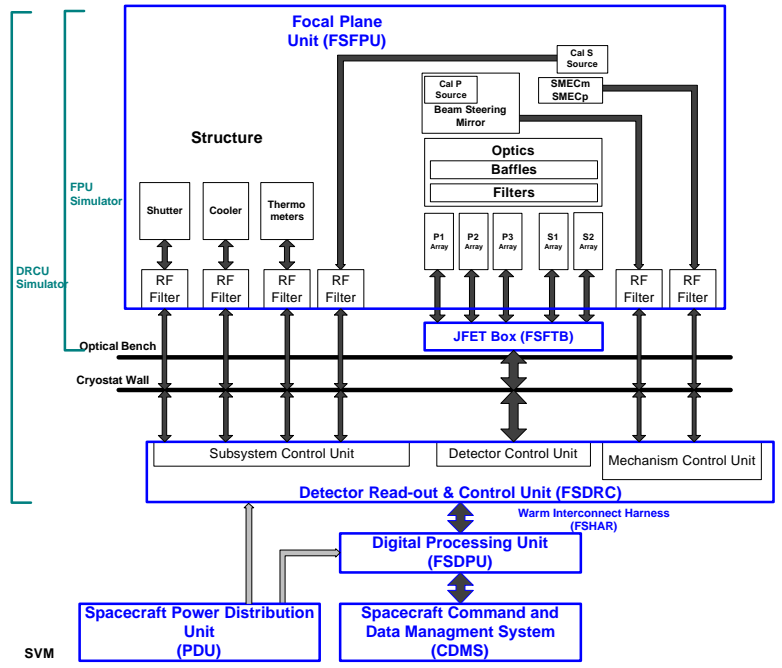


Figure 2-1 Instrument Block Diagram

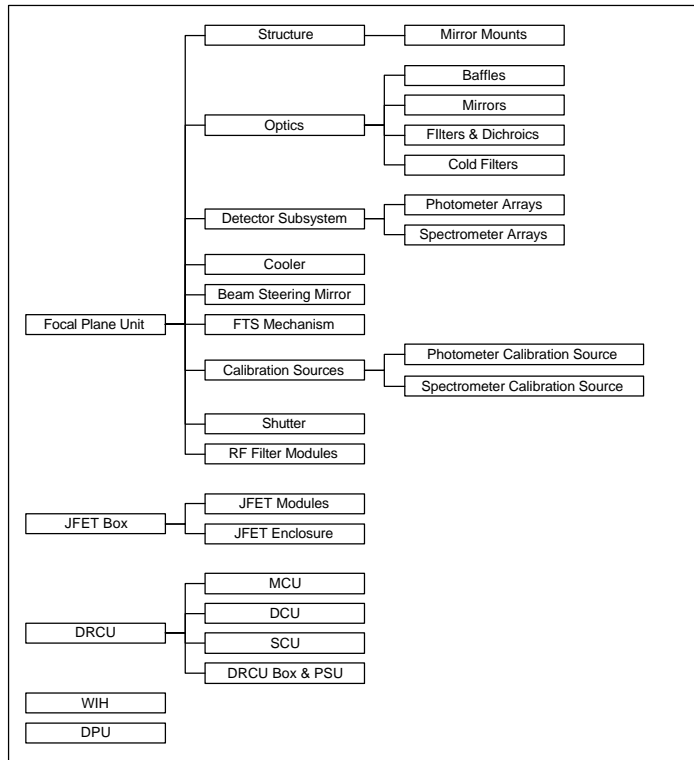
## 2.2 Model Philosophy

The following SPIRE models will be produced;

- Avionics Model (AVM)
- Structural Thermal Model (STM)
- Cryogenic Qualification Model (CQM)
- Electronics Qualification Model (EQM)
- Proto-Flight Model (PFM)
- Flight Spare Model (FS)
- 

The STM and EQM are for internal SPIRE use and will not be delivered to ESA

Additional qualification/test models of subsystems will be produced by each subsystem RO. These are detailed in the appropriate development plans. The following sections describe each model and **Table 2-1** summarises the contents of each model.



**Figure 2-2 Instrument Product Tree**

**2.2.1 Avionics Model (AVM).**

This model is required to validate the instrument electronics and software and their interfaces with the S/C. This will include:

- verification of information exchange with the S/C computer, mass memory and attitude control systems
- verification of the instrument autonomy functions

- validation of on-board software updates
- validation of AIV procedures

The AVM will consist of a DPU (FSDPU) plus a DRCU Simulator. The DRCU Simulator will provide sufficient simulation of the operation of the FPU, DRCU and WIH to allow the activities given above to be carried out.

The DPU will be built to flight representative standards using commercial parts, where possible with the same technology and from the same supplier as the PFM. This model will be form and fit identical to the PFM but will not implement any redundancy.

In addition the AVM DPU will be used during testing of the CQM (see below) both at instrument-level and during CQM testing at ESA.

### 2.2.2 Structural Thermal Model

This model is provided early in the development phase. Its purpose is;

- to gain confidence in the mechanical model of the structure, by comparison of the vibration response when warm with the Finite Element Analysis.
- to validate the thermal model of the instrument at the higher temperature levels (2K, 4K and 10K)
- to verify the optical alignment procedure

The model is not complete in itself. It consists of the CQM structure with additional mass/thermal models of subsystems (some also acting as optical dummies) integrated.

### 2.2.3 Cryogenic Qualification Model

This model will be used by the SPIRE consortium to qualify the cold instrument design against the proposed environmental test levels. On delivery to ESA it will be used to ensure the compatibility of the FIRST payload and spacecraft by performing a series of functional tests and a set of conductive EMC tests in the ISO Flight Spare Cryostat.

This model consists of an FPU (FSFPU and FSFTB). In addition, to allow its integration and test, the following units will be provided; DRCU, WIH, FPU Simulator and EGSE. It is assumed that the AVM DPU will be available for use for the duration of the CQM tests.

The CQM FPU will be built to flight standards with full redundancy. The performance capabilities of the instrument may be less than the PFM - i.e. fewer pixels in the focal plane arrays, but it will mimic as exactly as possible the thermal, electrical and mechanical properties of the flight instrument and will be capable of under going the full environmental qualification programme.

The DRCU will be built from non-flight grade components, but will be form and fit identical to the PFM. It will not provide any redundancy.

### 2.2.4 Electronics Qualification Model

This additional model is built to allow qualification testing of the warm electronics units independently of the CQM test programme. The following tests will be performed at the instrument level:

- EMC tests (Conduction, Emission, Susceptibility)

- Thermal Vacuum Test (TBC, the individual units will be tested by the ROs)
- Warm Vibration (TBC, the individual units will be tested by the ROs)

This model will be used to carry out the first testing of the PFM FPU while the PFM electronics is being manufactured.

The model consists of a DPU, DRCU and WIH. Each will be electrically, thermally and mechanically representative of the flight units, including redundancy. Components will be of the same type as the flight model, but at a lower quality level.

#### 2.2.5 Proto-Flight Model

This is the instrument model that is intended for flight. It consists of all SPIRE Instrument Units. It will be built to full flight standards and will only have minor differences in thermal, electrical and mechanical properties to the CQM. It will have the same mechanical, thermal and electrical interfaces to the satellite as the CQM but, may, however, have minor internal design changes compared to the CQM. For instance the bolometer arrays may have many more pixels.

The PFM will undergo environmental testing to qualification levels for acceptance times - this applies to both the warm electronics boxes and the cold FPU.

#### 2.2.6 Flight Spare Model

The Flight Spare Model provides for replacement of failed, or damaged, units during system level testing.

The FS will consist of a full flight standard, calibrated (TBC) FPU and tested spare parts (normally at board level) for the DPU, DRCU and BAU.

It is possible that the Flight Spare Units may be provided from refurbished AVM and CQM units.

	AVM	CQM	EQM	PFM	FS	Comments
<b>Instrument Units</b>						
FPU		CQM		PFM	FS	
FET Box		CQM		PFM	FS	
DRCU		QM1	QM2	PFM	FS <sup>1</sup>	
WIH		QM1	QM2	PFM	FS	
DPU	AVM		EQM	PFM	FS <sup>2</sup>	AVM Unit will be used for CQM testing at ESA
<b>Support Equipment</b>						
FPU Simulator		#1	#2			One unit (#1) will remain at ESA for use with all models
DRCU Simulator		#3				
EGSE		#4				One unit (#4) will remain at ESA for use with all models

## Notes:

1. Possibly only spare cards will be provided
2. Only spare cards (shared with other FIRST instruments) will be provided

**Table 2-1 Instrument Model summary of constituent Units**

## 2.3 Qualification and verification

Qualification and verification of the instrument will be carried out both at subsystem and instrument levels;

1. All sub-systems will go through a type approval programme of one or more models, as necessary, before the Cryogenic Qualification version of the sub-system is delivered for the instrument AIV. The testing carried out on the CQM instrument is not considered to be the qualification test for each individual sub-system as the tests carried out on the instrument CQM will be neither exhaustive nor at the correct level for sub-system qualification.
2. The CQM will undergo a series of qualification and compatibility tests at levels and temperatures agreed between SPIRE and ESA.
3. Acceptance tests will be performed on each subsystem prior to delivery for the PFM and FS models.
4. An acceptance test programme will be performed on the instrument prior to delivery to ESA.
5. Characterisation and calibration of the subsystems will be made prior to delivery of all models.
6. Characterisation and calibration of the instrument will be made prior to delivery of all models.

### 2.3.1 Qualification Tests

Vibration:	All sub-systems are to be vibrated at levels appropriate to their location within the instrument. The temperature at which the vibration will be done is subject to negotiation between the project and ESA. The group responsible for the structure will define the level at which each sub-system will be vibrated. This will either be by calculation or vibration of test structures.
Thermal cycle:	All FPU sub-systems will be cooled down and warmed up a large number of times over the period leading up to launch. An accelerated thermal cycle test is therefore required for <u>all</u> FPU sub-systems. The temperatures, rate of temperature change and number of cycles are TBD.
Vacuum cycle:	All sub-systems will be operating <i>in vacuo</i> . The long-term performance of all sub-systems <i>in vacuo</i> as well as their response to vacuum cycling must be assessed. All sub-systems will be vacuum cycled and critical items will undergo long-term life tests under vacuum conditions.
Lifetime:	Where novel material processing or unqualified mechanisms are employed in a sub-system, accelerated life tests will be mandatory. For all ASICs and micro-machined components a programme of device selection will be required to guard against infant mortality.

Soak/cycle:	All electronic sub-systems and/or components will need to be soak tested and operationally cycled as part of their lifetime test programme.
Radiation tolerance:	All unqualified electronics sub-systems and/or components will have to be exposed to the appropriate level of radiation dose to ensure survival in orbit.
Thermal range:	The operating temperature range of a sub-system will be characterised. If a sub-system does not operate within specification, or at all, at temperatures that are within the expected limits, it cannot be considered qualified.
Thermal stability:	The response of a sub-system to thermal instabilities will be characterised as will the impact of sub-system operation on the thermal stability of the instrument. A sub-system that <u>causes</u> large thermal instability in the instrument during its normal operational cycle or is over sensitive to the expected level of thermal instability cannot be considered qualified.
Microphonics:	The level of mechanical vibration from a sub-system will be characterised as well as the response of the sub-system to microphonic interference. Any sub-system that causes excessive mechanical vibration during its normal operation or is over sensitive to the expected level of mechanical vibration cannot be considered qualified.
Ionising radiation:	The response of a sub-system (e.g. the detectors) to high energy ionising radiation (simulating cosmic ray proton hits), will be characterised. A sub-system will not be considered qualified if its performance is significantly reduced by the impact of high energy ionising radiation.
EMI:	The sensitivity of a sub-system to electromagnetic interference will be characterised. If a sub-system is over sensitive to the expected level of electromagnetic emission it will be deemed not qualified.
EMC:	The radiated and conducted electromagnetic emission of a sub-system will be characterised. Any sub-system that emits significant levels of electromagnetic radiation or interferes with power supplies or ground lines will not be considered qualified.
Materials conformance:	All materials used in the manufacture of a sub-system must be approved for space use by ESA. Any materials not on an approved list must under go a materials approval test as laid down by ESA.

### 2.3.2 Subsystem Qualification

**Table 2-2** is the test matrix for the SPIRE sub-systems qualification programme. Tests marked with an X are mandatory, those marked with a P are possibly required depending on the detailed design of the sub-system and/or the new of novel materials.

	Structure	Optics	FTS Mechanism	Chopper	Detector arrays	Cooler	Filters/grids/dichroics	Calibration Sources	DCRU	DPU
Vibration:	X	X	X	X	X	X	X	X	X	X
Thermal cycle:	X	X	X	X	X	X	X	X		
Vacuum cycle			X	X	X	X	X	X	X	X
Lifetime:		P	X	X	X	X	X	X	X	X
Soak/cycle:			X	X	X	X		X	X	X
Radiation tolerance:			P	P	X	P	X	X	X	X
Thermal range:			X	X	X	X	X	X	X	X
Thermal stability:		P	X	X	X	X	P	X	X	X
Microphonics:		P	X	X	X	X	P	P		
Ionising radiation:					X					
EMI:			X	X	X	P		P	X	X
EMC:			X	X	X	P		P	X	X

**Table 2-2 Test Matrix for Subsystem Qualification**

For some sub-systems the qualification and lifetime testing will be more appropriately carried out at component or test item level rather than at the level of the integrated sub-system. At what stage and under what conditions the tests are to be carried out is a matter for detailed consideration by the groups responsible for the sub-systems delivery.

### 2.3.3 Instrument-level Qualification

**Table 2-3** is the test matrix for the instrument level testing. Q indicates a test carried out at qualification level for qualification times; QA a test carried out at qualification levels for acceptance test times and A a test carried out at acceptance level for acceptance times. An x indicates that this test is carried out and is a characterisation type test or the level is irrelevant. A dash indicates that no test will be done on this model/unit.

	CQM FPU	CQM DCRU	CQM SPU	CQM DPU	PFM FPU	PFM DCRU	PFM DPU	FS Focal Plane Unit	FS DCRU	FS DPU
Vibration:	Q	Q	Q	Q	QA	QA	QA	A	A	A
Thermal cycle:	Q	Q	Q	Q	QA	QA	QA	A	A	A



Vacuum cycle	x	x	x	x	x	x	x	x	x	x
Thermal range:	x	x	x	x	x	x	x	-	-	-
EMC (Instrument Level)	x	x	x	x	x	x	x	-	-	-
EMC (Satellite Level):	-	-	-	-	x	x	x	-	-	-

**Table 2-3 Test Matrix for Instrument-level Testing**

### 3. DEVELOPMENT OF SPIRE SUB-SYSTEMS

Figure 2-2 has shown the breakdown of the instrument into subsystems. Figure 3-1 shows how these subsystems are assembled to for the instrument units.

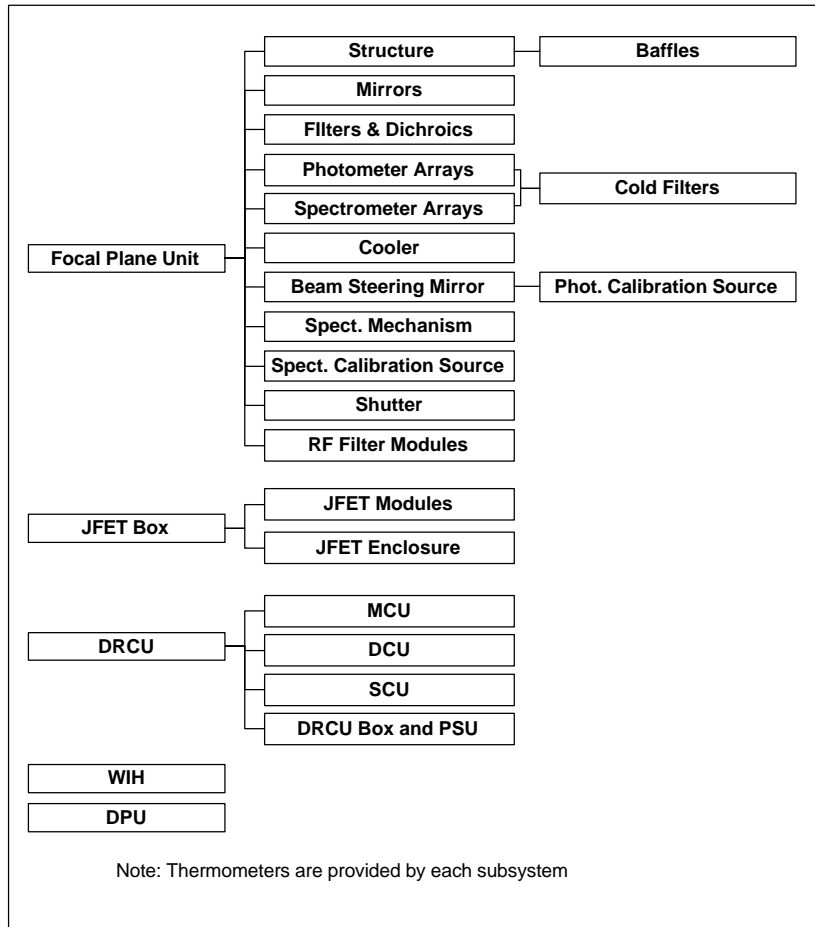


Figure 3-1 Instrument Assembly Tree

**3.1 Focal Plane Unit**

Table 3-1 is a summary of the FPU subsystem models to be delivered;

	Resp.	STM	CQM	PFM	FS	To	Comments
<b>FPU Subsystems</b>							
Structure	MSSL		CQM	PFM	FS	RAL	
Mirror Mounts	MSSL		CQM	PFM	FS	RAL	
Optics							
Mirrors	LAS		CQM	PFM	FS	RAL	
Filters & Dichroics	QMW	??	CQM	PFM	FS	RAL	
Cold Filters	QMW		CQM	PFM	FS	JPL	
Baffles	MSSL		CQM	PFM	FS	RAL	
Detectors							
Photometer Array 1	JPL	STM	CQM	PFM	FS	RAL	
Photometer Array 2	JPL	STM	CQM	PFM	FS	RAL	
Photometer Array 3	JPL	STM	CQM	PFM	FS	RAL	
Spectrometer Array 1	JPL	STM	CQM	PFM	FS	RAL	
Spectrometer Array 2	JPL	STM	CQM	PFM	FS	RAL	
Cooler	Grenoble	STM	CQM	PFM	FS	RAL	
Beam Steering Mirror	ATC	OD	CQM	PFM	FS	LAM	Optical Dummy delivered to RAL
FTS Mechanism	LAM	OD	CQM	PFM	FS	RAL	
Calibration Sources							
Photometer	QMW		CQM	PFM	FS	ATC	
Spectrometer	QMW	STM	CQM	PFM	FS	RAL	
Shutter	USK						
RF Filter Modules	JPL	STM	CQM	PFM	FS	RAL	

Table 3-1 FPU Subsystem Deliverables

### 3.2 JFET Box

The table below gives a summary of the subsystems to be delivered;

	Resp.	STM	CQM	PFM	FS	To	Comments
<b>JFET Box Subsystems</b>							
JFET Modules	JPL		CQM	PFM	FS	RAL	
JFET Enclosure	MSSL/RAL	???	CQM	PFM	FS	RAL	

Table 3-2 FET Box Subsystem Deliverables

### 3.3 DRCU

The table below gives a summary of the subsystems to be delivered;

	Resp.	CQM	EQM	PFM	FS	To	Comments
<b>DRCU Subsystems</b>							
MCU	LAM	QM1	QM2	PFM	FS	SAP	

DCU	SAP	QM1	QM2	PFM	FS		
SCU	SAP	QM1	QM2	PFM	FS		
DRCU Box and PSU	SAP	QM1	Qm2	PFM	FS		

**Table 3-3 DRCU Subsystem Deliverables**

### 3.4 WIH

The table below gives a summary of the subsystems to be delivered;

	Resp.	CQM	EQM	PFM	FS	To	Comments
<b>WIH Subsystems</b>							
WIH	SAP	QM1	QM2	PFM	FS	RAL	

**Table 3-4 WIH Subsystem Deliverables**

### 3.5 DPU

The table below gives a summary of the subsystems to be delivered;

	Resp.	AVM	EQM	PFM	FS	To	Comments
<b>DPU Subsystems</b>							
DPU	IFSI	AVM	EQM	PFM	FS	RAL	

**Table 3-5 DPU Subsystem Deliverables**

#### 4. TEST AND SUPPORT EQUIPMENT AND FACILITIES

The table below gives a summary of the test and support equipment and facilities required for development, test and calibration of the instrument models.

	Resp.	No.	To	Comments
<b>Simulators</b>				
FPU Simulator	SAP	2	RAL	One is delivered to ESA
DRCU Simulator	SO	3	IFSI/RAL(2)	One is delivered to ESA
<b>Support Equipment</b>				
EGSE	RAL	3	RAL	One is delivered to ESA
<b>Test Facilities</b>				
Calibration Cryostat	RAL	1		
Telescope Simulator	RAL	1		

Table 4-1 Test and Support Equipment Deliverables

## **5. SPIRE INTEGRATION AND TEST**

All integration and testing at instrument-level is the responsibility of RAL. RAL will make use of its own facilities wherever possible for testing and requires only external facilities to perform the cold vibration of the CQM, PFM and FS models. It is assumed that ESA will provide these facilities.

The majority of the instrument-level testing will take place in the RAL Test Facility described in RD14.

The AIV Plan (RD20) details the steps that each of the instrument models undergoes during the integration, verification and calibration stages after delivery to RAL and before delivery to ESA.

## 6. SPIRE DEVELOPMENT AND SCHEDULE

### 6.1 Overall Schedule for the FIRST Programme

Table 6-1 shows the current ESA high-level milestones defined for the FIRST development phases and the delivery dates of the instrument models.

Milestone	Date
Issue of ITT to industry	September 2000
Start Phase B	June 2001
Start of Phase C/D	June 2002
End of Phase C/D	July 2006
Launch	Q1 2007
Delivery of Instrument AVM	April 2003
Delivery of Instrument CQM	April 2003
Delivery of Instrument PFM	July 2004
Delivery of Instrument FS	July 2005

**Table 6-1 ESA High-level Milestones**

Figure 6-1 shows the corresponding SPIRE baseline development schedule, which meets these milestones. A list of the instrument Major milestones is given in Appendix 1. Detailed Schedules for each Instrument deliverable model and each subsystem are given in Appendix 2



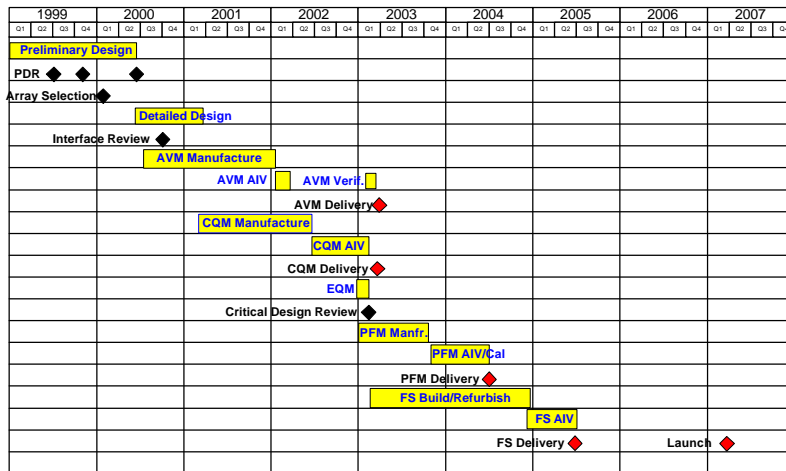


Figure 6-1 SPIRE Overall Schedule

#### Annex 1. LIST OF MILESTONES

Name	Resp.	Date
Detector Selection		Tue 1/2/00
Detector STM Delivery to RAL	JPL	Fri 1/2/02
Cooler STM Delivery to RAL	Grenoble	Fri 1/2/02
Shutter STM Delivery to RAL	USK	Fri 1/2/02
Spectrometer Calibration Source STM Delivery to RAL	QMW	Fri 1/2/02
CQM RF Filter Modules Delivery to RAL		Fri 1/2/02
Deliver Simulink Model to LAM	ATC	Fri 11/8/00
Deliver Analogue Board Design Doc to LAM	ATC	Fri 11/8/00
Deliver Prototype2 to LAM	ATC	Wed 13/9/00
Deliver Analogue Board Detailed Design to LAM	ATC	Mon 1/1/01
Delta PDR	RAL	Mon 26/6/00
Instrument Interface Review	RAL	Mon 9/10/00
"Structure, Optics, Cooler Detailed Design Review"		Mon 19/3/01
"SMEC, BSM Detailed Design Review"		Wed 31/1/01
WE Detailed Design Review		Tue 3/10/00
Deliver DM2 to LAM	ATC	Fri 30/3/01
CQM BSMm Delivery to LAM	ATC	Wed 13/3/02
CQM Arrays First Delivery to QMW	JPL	Fri 23/11/01
CQM Sparse Arrays Delivery to QMW	JPL	Fri 23/11/01
CQM JFET Modules Delivery to RAL		Fri 1/3/02
SMECm Simulator Delivery to SAp	LAM	Tue 20/2/01
MCU EM Delivery to Sap	LAM	Fri 21/9/01
QM1 MCU delivery to Sap	LAM	Fri 21/9/01
QM2 MCU Delivery to Sap	LAM	Wed 10/7/02
CQM Structure ready for Integration	MSSL	Fri 5/7/02
CQM Mirrors + OGSE Delivery to RAL	LAM	Fri 1/3/02
"STM/Alignment Filter, Dichroics and Beamsplitters Delivery to RAL"	QMW	Fri 1/3/02
BSM STM/Optical Dummy Delivery to RAL	ATC	Fri 1/3/02
SMECm STM/Optical Dummy Delivery to RAL	LAM	Fri 1/3/02
CQM PCAL Delivery to ATC	QMW	Thu 1/11/01
STM Test Review		Fri 5/7/02
CQM Detector Arrays Delivery to RAL	JPL	Sat 1/6/02
CQM SCAL Delivery to RAL	QMW	Sat 1/6/02
CQM SMECm Delivery to RAL	LAM	Sat 1/6/02
CQM BSMm Delivery to RAL	ATC	Sat 1/6/02
CQM Cooler Delivery to RAL	Grenoble	Sat 1/6/02
CQM Shutter Delivery to RAL	USK	Sat 1/6/02
CQM Filters Dichroics and Beamsplitters Delivery to RAL	QMW	Sat 1/6/02
CQM JFET Box Delivery to RAL	JPL	Sat 1/6/02
CQM RF Filter Modules Delivery to RAL		Sat 1/6/02
EGSE#1 Delivery to IFSI	PACS	Fri 1/6/01
DRCU Simulator#1 Delivery to IFSI	SO	Fri 1/6/01
DRCU Simulator#2 Delivery to RAL	SO	Fri 1/2/02
FPU Simulator#1 Delivery to RAL	SAP	Wed 1/5/02
AVM DPU Delivery to RAL	IFSI	Fri 1/2/02
QM1 DRCU Delivery to RAL	SAP	Wed 1/5/02
QM1 WIH Delivery to RAL	SAP	Wed 1/5/02
Test Facility Available	RAL	Fri 10/5/02
EGSE#2 Available	RAL	Fri 1/2/02

EGSE#3 Available	RAL	Fri 15/3/02
Delivery of CQM FPU to Cold Vibration Facility	RAL	Wed 23/10/02
Delivery of Cold-Vibrated CQM FPU to RAL	RAL	Wed 20/11/02
FPU Critical Design Review		Sat 1/2/03
EGSE#4 Available	RAL	Wed 1/1/03
CQM Delivery to ESA	RAL	Tue 1/4/03
QM DPU Delivery to RAL	IFSI	Wed 1/1/03
DRCU Simulator#3 to RAL	SO	Wed 1/1/03
QM2 DRCU Delivery to RAL	SAP	Mon 20/1/03
QM2 WIH Delivery to RAL	SAP	Mon 20/1/03
FPU Simulator#2 Delivery to RAL	SAP	Mon 20/1/03
WE Critical Design Review		Thu 20/3/03
AVM Delivery to ESA	RAL	Tue 1/4/03
PFM BSMm Delivery to LAM	ATC	Thu 11/9/03
PFM MCU Delivery to SAP	LAM	Tue 24/6/03
PFM Arrays First Delivery to QMW	JPL	Fri 1/8/03
PFM Arrays last Delivery to QMW	JPL	Wed 1/10/03
PFM PCAL Delivery to ATC	QMW	Thu 26/6/03
PFM JFET Modules Delivered to RAL	JPL	Mon 2/2/04
PFM Structure Ready for Integration	MSSL	Mon 1/9/03
PFM Mirrors Delivery to RAL	LAM	Fri 15/8/03
PFM Detector Arrays Delivery to RAL	JPL	Sat 1/11/03
PFM SCAL Delivery to RAL	QMW	Mon 1/12/03
PFM SMEC Delivery to RAL	LAM	Mon 1/12/03
PFM BSM Delivery to RAL	ATC	Mon 1/12/03
PFM Cooler Delivery to RAL	Grenoble	Mon 1/12/03
PFM Shutter Delivery to RAL	USK	Mon 1/12/03
PFM Filters Dichroics and Beamsplitters Delivery to RAL	QMW	Sat 1/11/03
PFM JFET Box Delivery to RAL		Mon 1/12/03
PFM RF Filter Modules Delivery to RAL		Sat 1/11/03
Delivery of PFM FPU to Cold Vibration Facility	RAL	Wed 18/2/04
Delivery of Cold-Vibrated PFM FPU to RAL	RAL	Wed 10/3/04
PFM DPU Delivery to RAL	IFSI	Wed 25/2/04
PFM DRCU Delivery to RAL	SAP	Mon 15/3/04
PFM WIH Delivery to RAL	SAP	Mon 15/3/04
PFM Delivery to ESA	RAL	Thu 1/7/04
Return of CQM from ESA	ESA	Mon 29/3/04
Delivery of QM DPU to IFSI	RAL	Thu 1/7/04
Delivery of QM2 DRCU to SAP	RAL	Thu 1/7/04
FS BSMm Delivery to LAM	ATC	Fri 2/1/04
FS Arrays First Delivery to QMW	JPL	Mon 2/8/04
FS Arrays last Delivery to QMW	JPL	Fri 1/10/04
FS PCAL Delivery to ATC	QMW	Fri 17/10/03
FS MCU Delivery to SAP	LAM	Tue 19/8/03
FS Structure Available for Integration	MSSL	Mon 1/11/04
FS Detector Arrays Delivery to RAL	QMW	Wed 10/11/04
FS SCAL Delivery to RAL	QMW	Wed 10/11/04
FS Cooler Delivery to RAL	Grenoble	Wed 10/11/04
FS Mirrors Delivery to RAL	LAM	Wed 10/11/04
FS SMECm Delivery to RAL		Wed 10/11/04
FS BSM Delivery to RAL	ATC	Wed 10/11/04
FS DPU Delivery to RAL	IFSI	Wed 10/11/04
FS Filters Dichroics and Beamsplitters Delivery to RAL	QMW	Wed 10/11/04
FS JFET Box Delivery to RAL		Wed 10/11/04

FS RF Filter Modules Delivery to RAL		Wed 10/11/04
MSSL (Version 0.4)	MSSL	Tue 1/7/97
Travel & Subsidence	MSSL	Tue 1/7/97
Travel Europe	MSSL	Thu 11/6/98
Travel outside Europe	MSSL	Thu 11/6/98
Travel UK	MSSL	Thu 11/6/98
Courses	MSSL	Tue 1/7/97
Pre-PDR	MSSL	Tue 20/7/99
PDR-interbellum	MSSL	Wed 2/7/97
Coupon testing	MSSL	Tue 20/7/99
Coupon definition	MSSL	Tue 20/7/99
Coupon production	MSSL	Mon 20/9/99
Coupon testing	MSSL	Mon 29/11/99
Coupon evaluation	MSSL	Mon 7/2/00
Drafting Concept	MSSL	Tue 20/7/99
Computing	MSSL	Wed 2/7/97
Alignment plan	MSSL	Mon 2/8/99
FEM concepts	MSSL	Fri 6/8/99
Defining interfaces	MSSL	Tue 3/8/99
Structure PDR	Project	Tue 27/6/00
Final Design	MSSL	Mon 10/4/00
Support test	MSSL	Thu 15/6/00
design test fixture	MSSL	Thu 15/6/00
design blade	MSSL	Thu 15/6/00
design fixed support	MSSL	Thu 22/6/00
support production	MSSL	Thu 13/7/00
support test	MSSL	Thu 27/7/00
Support test evaluation	MSSL	Thu 10/8/00
Drafting Final	MSSL	Thu 13/7/00
Spectrometer Mirror support	MSSL	Thu 13/7/00
Support corner mirror	MSSL	Thu 13/7/00
Support collimated mirror	MSSL	Thu 20/7/00
Spect. beam splitters support	MSSL	Thu 27/7/00
Spect. beam split. support	MSSL	Thu 27/7/00
Spect. Det. box	MSSL	Thu 3/8/00
Bottom	MSSL	Thu 3/8/00
Middle	MSSL	Mon 14/8/00
Top	MSSL	Wed 23/8/00
Photometer mirror support	MSSL	Thu 10/8/00
Secondary Opt. Bench	MSSL	Thu 10/8/00
M6 support	MSSL	Thu 31/8/00
M8 support	MSSL	Thu 21/9/00
Phot. Det. Box	MSSL	Fri 29/9/00
Bottom	MSSL	Fri 29/9/00
Middle	MSSL	Wed 11/10/00
Top	MSSL	Mon 23/10/00
Baffles	MSSL	Thu 13/7/00
Common structure	MSSL	Thu 2/11/00
Detector Box support	MSSL	Mon 19/3/01
Optical bench panel	MSSL	Thu 2/11/00
Side panel 1	MSSL	Tue 5/12/00
Side panel 2	MSSL	Wed 13/12/00
Side panel 3	MSSL	Thu 21/12/00
Side panel 4	MSSL	Fri 29/12/00
Side panel 5	MSSL	Mon 8/1/01
Side panel 6	MSSL	Tue 16/1/01

Side panel 7	MSSL	Wed 24/1/01
Side panel 8	MSSL	Thu 1/2/01
Cover panel +Y	MSSL	Fri 9/2/01
Cover Panel -Y	MSSL	Wed 28/2/01
Common structure Support	MSSL	Tue 27/3/01
Fixed point (final)	MSSL	Tue 27/3/01
Blade support (final)	MSSL	Thu 29/3/01
Final FEM	MSSL	Thu 15/6/00
Model creation	MSSL	Thu 15/6/00
Static Analysis	MSSL	Thu 7/9/00
Thermal deformation analysis	MSSL	Thu 28/9/00
Sine analysis	MSSL	Thu 19/10/00
Random analysis	MSSL	Thu 9/11/00
Shock Analysis	MSSL	Thu 30/11/00
MGSE design	MSSL	Thu 2/11/00
Interface plate	MSSL	Thu 2/11/00
OBP holder/Handling frame	MSSL	Thu 9/11/00
Transport Container	MSSL	Thu 21/12/00
Freeze interface definition	MSSL	Mon 10/4/00
Cooler	MSSL	Mon 10/4/00
FTS mechanism	MSSL	Fri 14/4/00
Mirrors	MSSL	Thu 20/4/00
Filters	MSSL	Wed 26/4/00
Baffles	MSSL	Tue 2/5/00
Shutter	MSSL	Mon 8/5/00
BMS	MSSL	Fri 12/5/00
Detectors	MSSL	Thu 18/5/00
S/C	MSSL	Wed 24/5/00
HiFi	MSSL	Tue 30/5/00
Spectrometer Calibration	MSSL	Mon 5/6/00
Photometer calibration	MSSL	Fri 9/6/00
Instrument Interface Review	MSSL	Tue 10/10/00
Structure Detailed Design Review	Project	Mon 19/3/01
CQM Structure Manufacture	MSSL	Mon 19/3/01
CQM Production	MSSL	Mon 19/3/01
Common structure	MSSL	Mon 19/3/01
Optical bench panel	MSSL	Mon 19/3/01
Cover panel +Y	MSSL	Mon 30/4/01
Cover Panel -Y	MSSL	Mon 21/5/01
Side panel 1	MSSL	Mon 11/6/01
Side panel 2	MSSL	Mon 25/6/01
Side panel 3	MSSL	Mon 9/7/01
Side panel 4	MSSL	Mon 23/7/01
Side panel 5	MSSL	Mon 6/8/01
Side panel 6	MSSL	Mon 20/8/01
Side panel 7	MSSL	Mon 3/9/01
Side panel 8	MSSL	Mon 17/9/01
Side panel 9	MSSL	Mon 1/10/01
Side panel 10	MSSL	Mon 15/10/01
MGSE production	MSSL	Mon 19/3/01
Interface plate	MSSL	Mon 19/3/01
OBP holder/Handling frame	MSSL	Mon 2/4/01
Transport Container	MSSL	Mon 4/6/01
Suspension	MSSL	Mon 30/7/01
Detector Box supports (6 x)	MSSL	Mon 30/7/01
Fixed point	MSSL	Wed 15/8/01

Blade +Y	MSSL	Wed 22/8/01
Blade -Y	MSSL	Wed 29/8/01
Dichroic and filter attachments	MSSL	Wed 5/9/01
Dichroic rings (2)	MSSL	Wed 5/9/01
Filters (2)	MSSL	Thu 13/9/01
Cold stops(3)	MSSL	Fri 21/9/01
Baffles	MSSL	Thu 4/10/01
Entry Photometer	MSSL	Thu 4/10/01
Separation Phot. 4 K - 2 K compartment	MSSL	Mon 22/10/01
Tube between Phot. - Spectr. entry	MSSL	Mon 12/11/01
Spectr. Mirror support	MSSL	Mon 19/3/01
Support Corner 1	MSSL	Mon 19/3/01
Support Corner 2	MSSL	Fri 23/3/01
Support Corner 3	MSSL	Thu 29/3/01
Support Corner 4	MSSL	Wed 4/4/01
Support Collimator 1	MSSL	Tue 10/4/01
Support Collimator 2	MSSL	Thu 19/4/01
Spectr. beam splitters support	MSSL	Mon 30/4/01
Spec.. beam split. supp. 1	MSSL	Mon 30/4/01
Spec.. beam split. supp. 2	MSSL	Fri 4/5/01
Photometer mirror support	MSSL	Thu 10/5/01
Secondary Opt. Bench	MSSL	Thu 10/5/01
M6 support	MSSL	Thu 14/6/01
M8 support	MSSL	Thu 5/7/01
Spectr. Det. box	MSSL	Thu 12/7/01
Bottom	MSSL	Thu 12/7/01
Top	MSSL	Thu 9/8/01
Phot.. Det. box	MSSL	Thu 30/8/01
Bottom	MSSL	Thu 30/8/01
Middle	MSSL	Thu 20/9/01
Top	MSSL	Thu 4/10/01
External Input	MSSL	Fri 4/1/02
Application Black Material (QMW)	MSSL	Fri 4/1/02
Thermal Finishes	MSSL	Fri 25/1/02
Structure Integration	MSSL	Thu 7/2/02
Integration Start	MSSL	Thu 7/2/02
Secondary OBP mounting	MSSL	Fri 8/2/02
OBP mounting in MGSE	MSSL	Mon 11/2/02
Mounting SDBX	MSSL	Tue 12/2/02
Mounting PDBX	MSSL	Wed 13/2/02
Photometer mirror support mounting	MSSL	Thu 14/2/02
Thermal Straps for detectors	MSSL	Fri 15/2/02
Beam splitters support mounting	MSSL	Mon 18/2/02
Spec.. mirror support mounting	MSSL	Tue 19/2/02
Mounting Baffles	MSSL	Wed 20/2/02
Mounting alignment tools? (OGSE?)	MSSL	Fri 22/2/02
Mounting sidepanels	MSSL	Mon 25/2/02
Mounting cover panels	MSSL	Fri 1/3/02
Mounting support for Common structure	MSSL	Tue 5/3/02
Ship to RAL	MSSL	Wed 6/3/02
Subsystem Deliveries	MSSL	Fri 1/2/02
Optics and OGSE Delivery to RAL	MSSL	Fri 1/3/02
Optics Acceptance	MSSL	Fri 1/3/02
STM/Alignment Filters Dichroics and Beamsplitters Delivery to RAL	MSSL	Fri 1/3/02
STM/Alignment Filters Dichroics and Beamsplitters	MSSL	Fri 1/3/02

Acceptance		
BSM STM/Optical Dummy Delivery to RAL	MSSL	Fri 1/3/02
BSM STM/Optical Dummy Acceptance	MSSL	Fri 1/3/02
SMEC STM/Optical Dummy Delivery to RAL	MSSL	Fri 1/3/02
FTS STM/Optical Dummy Acceptance	MSSL	Fri 1/3/02
Detector STM Delivery to RAL	MSSL	Fri 1/2/02
Cooler STM Delivery to RAL	MSSL	Fri 1/2/02
Shutter STM Delivery to RAL	MSSL	Fri 1/2/02
Spectrometer Calibration Source STM Delivery to RAL	MSSL	Fri 1/2/02
CQM RF Filter Modules Delivery to RAL	MSSL	Fri 1/2/02
CQM RF Filter Modules Acceptance	MSSL	Fri 1/2/02
Alignment verification	MSSL	Fri 8/3/02
Check alignment mechanical	MSSL	Fri 8/3/02
"Integrate mirrors, OGSE amd Optical Dummies"	MSSL	Fri 29/3/02
Integrate Mass Dummies	MSSL	Fri 19/4/02
Integrate RF Filter Modules	MSSL	Wed 24/4/02
Add Instrumentation	MSSL	Thu 25/4/02
Optical alignment check warm	MSSL	Fri 26/4/02
STM Warm Vibration	MSSL	Tue 30/4/02
visual inspection	MSSL	Tue 30/4/02
Mounting on shaker+instrum.	MSSL	Wed 1/5/02
"X-axis sine, random, shock"	MSSL	Fri 3/5/02
"Y-axis sine, random, shock"	MSSL	Fri 10/5/02
"Z-axis sine, random, shock"	MSSL	Fri 17/5/02
visual inspection	MSSL	Fri 24/5/02
Post STM Vibration Verification	MSSL	Mon 27/5/02
Optical alignment check warm	MSSL	Mon 27/5/02
Optical Quality Verification	MSSL	Mon 27/5/02
Bakeout	MSSL	Mon 10/6/02
Optical Alignment Check warm	MSSL	Mon 17/6/02
Test Cryostat Available	MSSL	Fri 10/5/02
Cold STM Testing	MSSL	Wed 19/6/02
Integration into Test Cryostat	MSSL	Wed 19/6/02
Cooldown	MSSL	Fri 21/6/02
Optical Alignment Check cold	MSSL	Wed 26/6/02
Thermal Balance Check	MSSL	Mon 1/7/02
Warm up	MSSL	Tue 2/7/02
STM De-integration	MSSL	Thu 4/7/02
Test Readiness Review	MSSL	Fri 5/7/02
PFM Structure Manufacture	MSSL	Wed 1/1/03
PFM production	MSSL	Wed 1/1/03
PFM Structure Ready for Integration	MSSL	Tue 26/8/03
FS Structure Manufacture	MSSL	Mon 29/3/04
CQM use by ESA	MSSL	Mon 29/3/04
FS refurbishment	MSSL	Tue 30/3/04
FS mechanical I/F check	MSSL	Tue 17/8/04
FS delivery to RAL	MSSL	Mon 1/11/04

**Annex 2. INSTRUMENT AIV SCHEDULES**



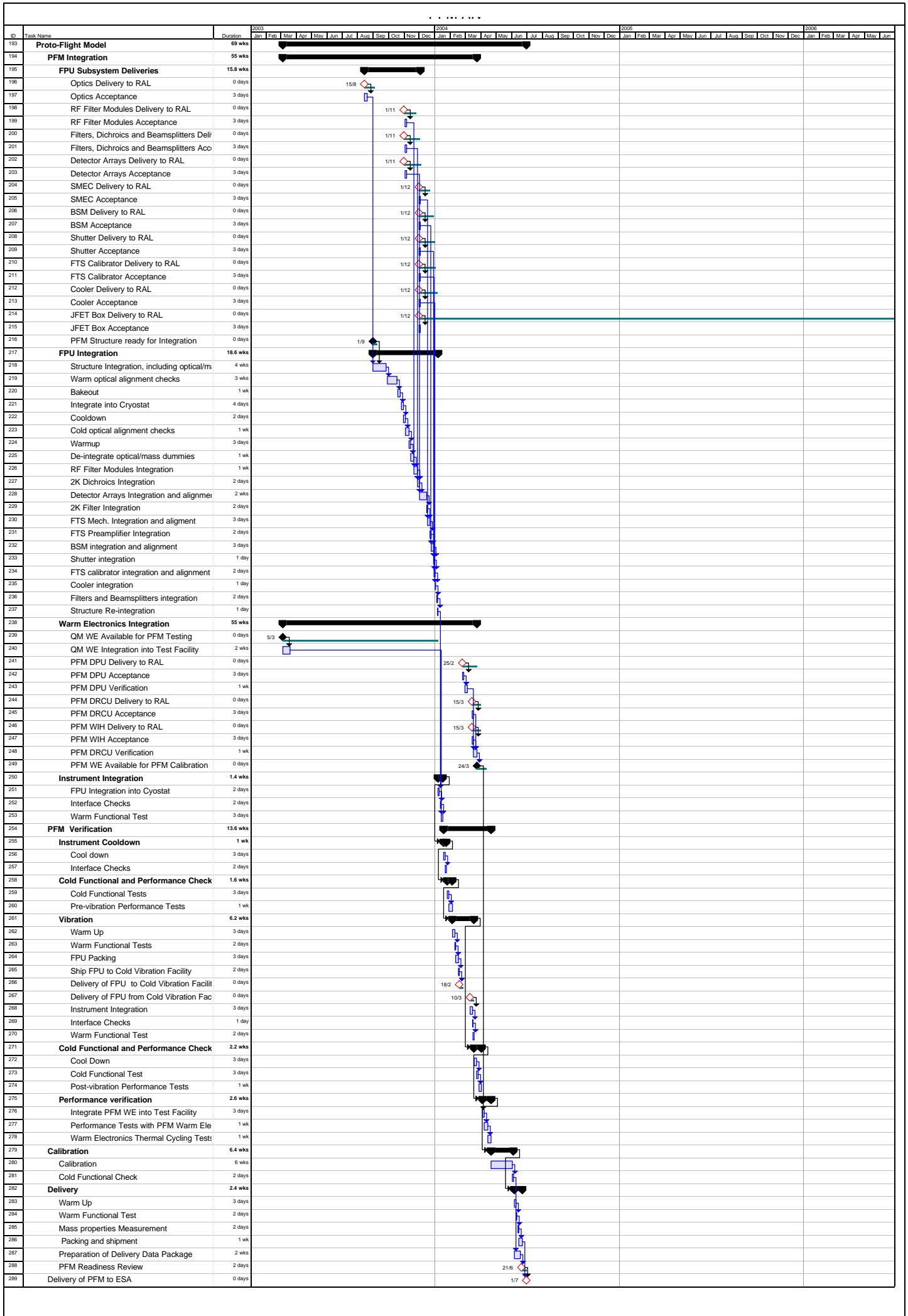
**AVM/AVY**

ID	Task Name	Duration	2002												2003												2004											
			Nov	Dec	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec	Jan	Feb	Mar	Apr						
80	<b>Avionics Model</b>	<b>55.6 wks</b>	[Gantt bar from Dec 2002 to Feb 2003]																																			
81	<b>Preliminary Integration</b>	<b>4.6 wks</b>	[Gantt bar from Dec 2002 to Feb 2003]																																			
82	AVM DPU Delivery to RAL	0 days	1/2	[Gantt bar from Jan 2003 to Feb 2003]																																		
83	AVM DPU Acceptance	3 days		[Gantt bar from Jan 2003 to Feb 2003]																																		
84	DRCU Simulator#2 Delivery to RAL	0 days	1/2	[Gantt bar from Jan 2003 to Feb 2003]																																		
85	DRCU Simulator#2 Acceptance	3 days		[Gantt bar from Jan 2003 to Feb 2003]																																		
86	EGSE#2 Available	0 days	1/2	[Gantt bar from Jan 2003 to Feb 2003]																																		
87	DPU Verification	4 wks		[Gantt bar from Jan 2003 to Feb 2003]																																		
88	AVM DPU Available for CQM Testing	0 days	5/3	[Gantt bar from May 2003 to Jun 2003]																																		
89	<b>AVM Verification</b>	<b>6.6 wks</b>	[Gantt bar from May 2003 to Jul 2003]																																			
90	AVM DPU Available for Delivery	0 days		[Gantt bar from May 2003 to Jul 2003]																																		
91	DRCU Simulator#3 Delivery to RAL	0 days		[Gantt bar from May 2003 to Jul 2003]																																		
92	EGSE#4 Available	0 days		[Gantt bar from May 2003 to Jul 2003]																																		
93	AVM Verification	2 wks		[Gantt bar from May 2003 to Jul 2003]																																		
94	<b>Delivery</b>	<b>3.4 wks</b>	[Gantt bar from May 2003 to Jul 2003]																																			
95	Preparation of Delivery Data Package	2 wks		[Gantt bar from May 2003 to Jul 2003]																																		
96	AVM Readiness Review	2 days		[Gantt bar from May 2003 to Jul 2003]																																		
97	Pack and Ship to ESA	1 wk		[Gantt bar from May 2003 to Jul 2003]																																		
98	AVM Delivery to ESA	0 days		[Gantt bar from May 2003 to Jul 2003]																																		

CQM FIV

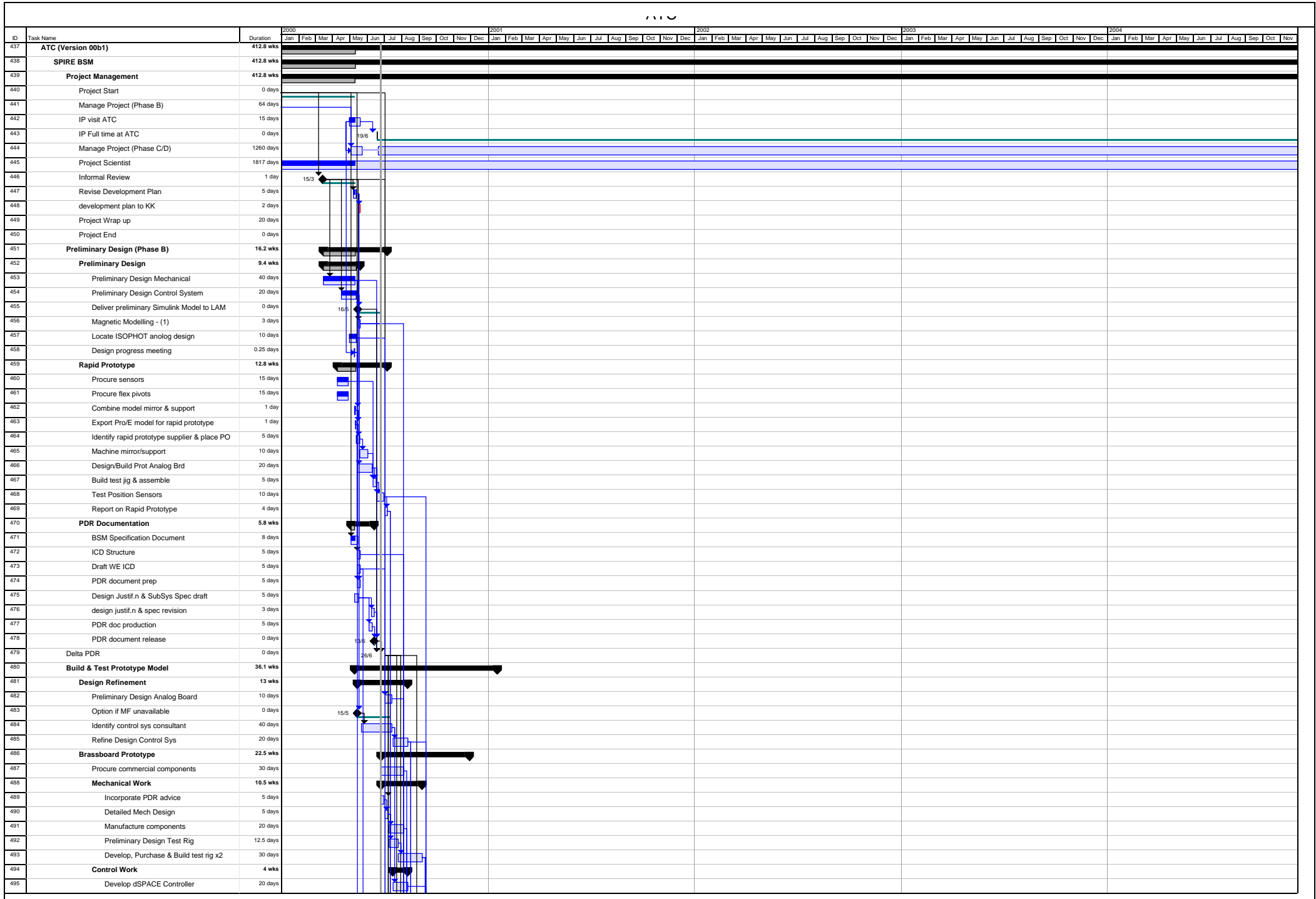
ID	Task Name	Duration	2002												2003												2004											
			Nov	Dec	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec	Jan	Feb	Mar	Apr						
99	<b>Cryogenic Qualification Model</b>	50.2 wks	[Timeline bar from Nov 2002 to Apr 2004]																																			
100	<b>CQM Integration</b>	11.2 wks	[Timeline bar from Nov 2002 to Dec 2002]																																			
101	<b>FPU Subsystem Deliveries</b>	5 wks	[Timeline bar from Nov 2002 to Dec 2002]																																			
102	Detector Arrays Delivery to RAL	0 days	[Timeline bar from May 2002 to May 2002]																																			
103	Detector Arrays Acceptance	3 days	[Timeline bar from May 2002 to May 2002]																																			
104	FTS Calibrator Delivery to RAL	0 days	[Timeline bar from May 2002 to May 2002]																																			
105	FTS Calibrator Acceptance	3 days	[Timeline bar from May 2002 to May 2002]																																			
106	SMEC Delivery to RAL	0 days	[Timeline bar from May 2002 to May 2002]																																			
107	SMEC Acceptance	3 days	[Timeline bar from May 2002 to May 2002]																																			
108	BSM Delivery to RAL	0 days	[Timeline bar from May 2002 to May 2002]																																			
109	BSM Acceptance	3 days	[Timeline bar from May 2002 to May 2002]																																			
110	Cooler Delivery to RAL	0 days	[Timeline bar from May 2002 to May 2002]																																			
111	Cooler Acceptance	3 days	[Timeline bar from May 2002 to May 2002]																																			
112	Shutter Delivery to RAL	0 days	[Timeline bar from May 2002 to May 2002]																																			
113	Shutter Acceptance	3 days	[Timeline bar from May 2002 to May 2002]																																			
114	Filters, Dichroics and Beamsplitters Del	0 days	[Timeline bar from May 2002 to May 2002]																																			
115	Filters, Dichroics and Beamsplitters Ac	3 days	[Timeline bar from May 2002 to May 2002]																																			
116	JFET Box Delivery to RAL	0 days	[Timeline bar from May 2002 to May 2002]																																			
117	JFET Box Acceptance	3 days	[Timeline bar from May 2002 to May 2002]																																			
118	CQM Structure ready for Integration	0 days	[Timeline bar from May 2002 to May 2002]																																			
119	<b>FPU Integration</b>	6.2 wks	[Timeline bar from May 2002 to Jun 2002]																																			
120	Detector Arrays Integration and alignme	2 wks	[Timeline bar from Jun 2002 to Jun 2002]																																			
121	2K Filter Integration	1 day	[Timeline bar from Jun 2002 to Jun 2002]																																			
122	SMECm Integration and alignment	3 days	[Timeline bar from Jun 2002 to Jun 2002]																																			
123	SMECp Integration	1 day	[Timeline bar from Jun 2002 to Jun 2002]																																			
124	BSM integration and alignment	3 days	[Timeline bar from Jun 2002 to Jun 2002]																																			
125	Shutter integration	1 day	[Timeline bar from Jun 2002 to Jun 2002]																																			
126	FTS calibrator integration and alignmen	2 days	[Timeline bar from Jun 2002 to Jun 2002]																																			
127	Cooler integration	1 day	[Timeline bar from Jun 2002 to Jun 2002]																																			
128	Filters, Dichroics and Beamsplitters inte	1 day	[Timeline bar from Jun 2002 to Jun 2002]																																			
129	Structure re-Integration and verification	5 days	[Timeline bar from Jun 2002 to Jun 2002]																																			
130	Integrate into Cryostat	3 days	[Timeline bar from Jun 2002 to Jun 2002]																																			
131	<b>Warm Electronics Integration</b>	16.6 wks	[Timeline bar from Jun 2002 to Sep 2002]																																			
132	AVM DPU Available for CQM Testing	0 days	[Timeline bar from Nov 2002 to Nov 2002]																																			
133	QM1 DRCU Delivery to RAL	0 days	[Timeline bar from Nov 2002 to Nov 2002]																																			
134	QM1 DRCU Acceptance	3 days	[Timeline bar from Nov 2002 to Nov 2002]																																			
135	QM1 WIH Delivery to RAL	0 days	[Timeline bar from Nov 2002 to Nov 2002]																																			
136	QM1 WIH Acceptance	3 days	[Timeline bar from Nov 2002 to Nov 2002]																																			
137	FPU Simulator#1 Delivery to RAL	0 days	[Timeline bar from Nov 2002 to Nov 2002]																																			
138	FPU Simulator#1 Acceptance	3 days	[Timeline bar from Nov 2002 to Nov 2002]																																			
139	DRCU Verification	4 wks	[Timeline bar from Nov 2002 to Dec 2002]																																			
140	EGSE#3 Available	0 days	[Timeline bar from Nov 2002 to Nov 2002]																																			
141	WE Integration into Test Facility	4 wks	[Timeline bar from Nov 2002 to Dec 2002]																																			
142	WE Available for CQM Testing	0 days	[Timeline bar from Dec 2002 to Dec 2002]																																			
143	Instrument Integration	1 wk	[Timeline bar from Dec 2002 to Dec 2002]																																			
144	CQM Test Readiness Review	1 day	[Timeline bar from Dec 2002 to Dec 2002]																																			
145	<b>Functional Testing</b>	3.8 wks	[Timeline bar from Dec 2002 to Jan 2003]																																			
146	Warm Functional Test	1 wk	[Timeline bar from Dec 2002 to Dec 2002]																																			
147	Cooldown	3 days	[Timeline bar from Dec 2002 to Dec 2002]																																			
148	Preliminary Cold Functional Test	1 day	[Timeline bar from Dec 2002 to Dec 2002]																																			
149	Cold Functional Test	2 wks	[Timeline bar from Dec 2002 to Jan 2003]																																			
150	Thermal Balance Checks	2 days	[Timeline bar from Dec 2002 to Dec 2002]																																			
151	<b>Vibration Testing</b>	9.4 wks	[Timeline bar from Jan 2003 to Feb 2003]																																			
152	Pre-Vibration Performance Checks	2 wks	[Timeline bar from Jan 2003 to Jan 2003]																																			
153	Warm Up	3 days	[Timeline bar from Jan 2003 to Jan 2003]																																			
154	Warm Functional Check	2 days	[Timeline bar from Jan 2003 to Jan 2003]																																			
155	FPU Packing	3 days	[Timeline bar from Jan 2003 to Jan 2003]																																			
156	Pack and Ship FPU to Cold Vibration Facil	2 days	[Timeline bar from Jan 2003 to Jan 2003]																																			
157	FPU Delivery to Cold Vibration Facility	0 days	[Timeline bar from Jan 2003 to Jan 2003]																																			
158	Delivery of Cold Vibrated CQM FPU to RAL	0 days	[Timeline bar from Jan 2003 to Jan 2003]																																			
159	Instrument re-integration	1 wk	[Timeline bar from Jan 2003 to Jan 2003]																																			
160	Warm Functional Check	2 days	[Timeline bar from Jan 2003 to Jan 2003]																																			
161	<b>Cold Functional and Performance Tests</b>	3.6 wks	[Timeline bar from Jan 2003 to Feb 2003]																																			
162	Cooldown	3 days	[Timeline bar from Jan 2003 to Jan 2003]																																			
163	Cold Functional Test	1 wk	[Timeline bar from Jan 2003 to Jan 2003]																																			
164	Post-vibration performance Check	2 wks	[Timeline bar from Jan 2003 to Jan 2003]																																			
165	Performance Verification	4 wks	[Timeline bar from Jan 2003 to Feb 2003]																																			
166	FPU Critical Design Review	0 days	[Timeline bar from Feb 2003 to Feb 2003]																																			
167	<b>Delivery Preparation</b>	4 wks	[Timeline bar from Feb 2003 to Mar 2003]																																			
168	Cold Functional Check	2 days	[Timeline bar from Feb 2003 to Feb 2003]																																			
169	Warm up	3 days	[Timeline bar from Feb 2003 to Feb 2003]																																			
170	Warm Functional Check	2 days	[Timeline bar from Feb 2003 to Feb 2003]																																			
171	Remove FPU from Cryostat	1 day	[Timeline bar from Feb 2003 to Feb 2003]																																			
172	Mass properties Measurement	2 days	[Timeline bar from Feb 2003 to Feb 2003]																																			
173	Packing and shipment	2 wks	[Timeline bar from Feb 2003 to Mar 2003]																																			
174	Preparation of Delivery Data Package	2 wks	[Timeline bar from Feb 2003 to Mar 2003]																																			
175	CQM Readiness Review	2 days	[Timeline bar from Mar 2003 to Mar 2003]																																			
176	Delivery of CQM to ESA	0 days	[Timeline bar from Mar 2003 to Mar 2003]																																			

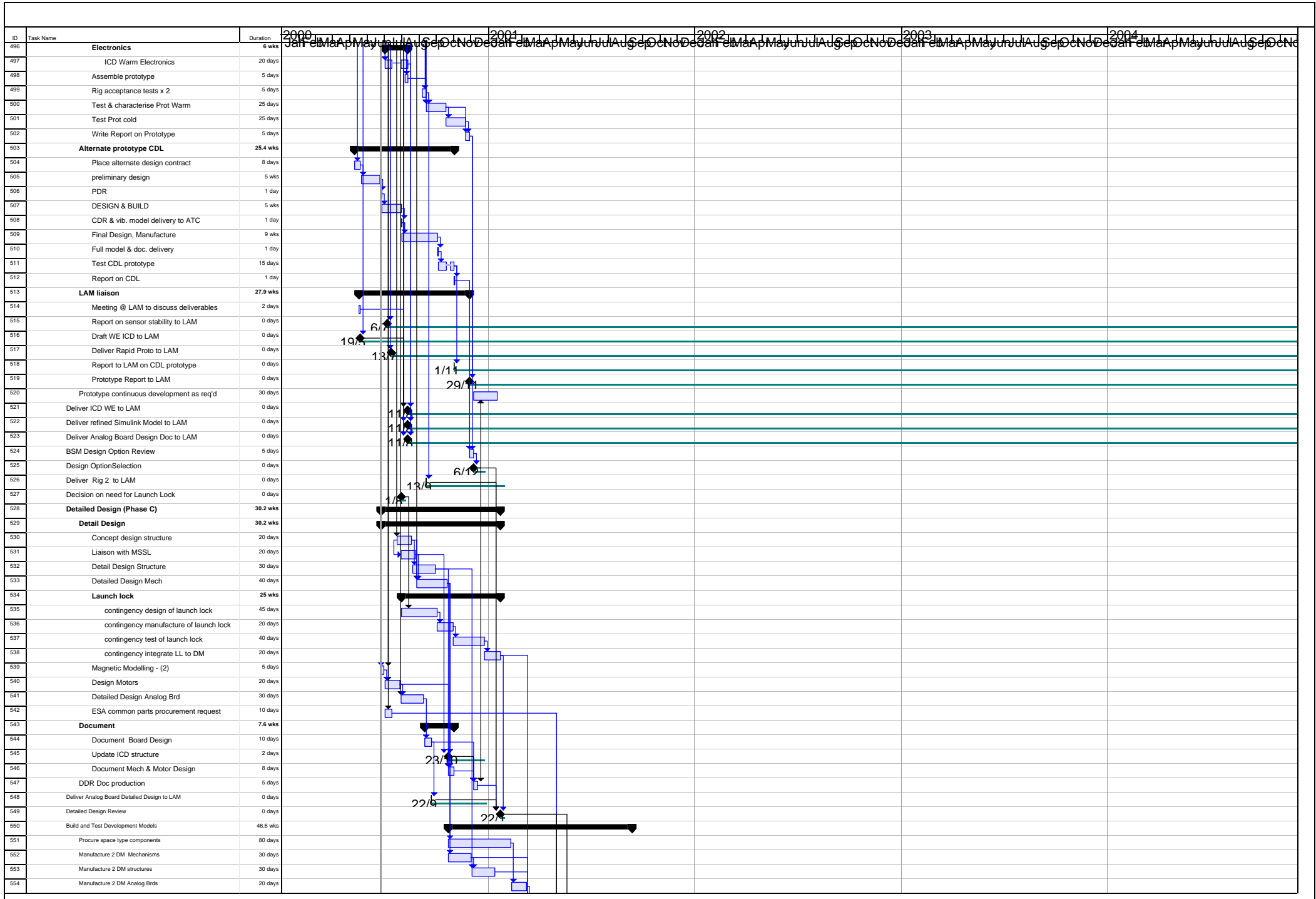




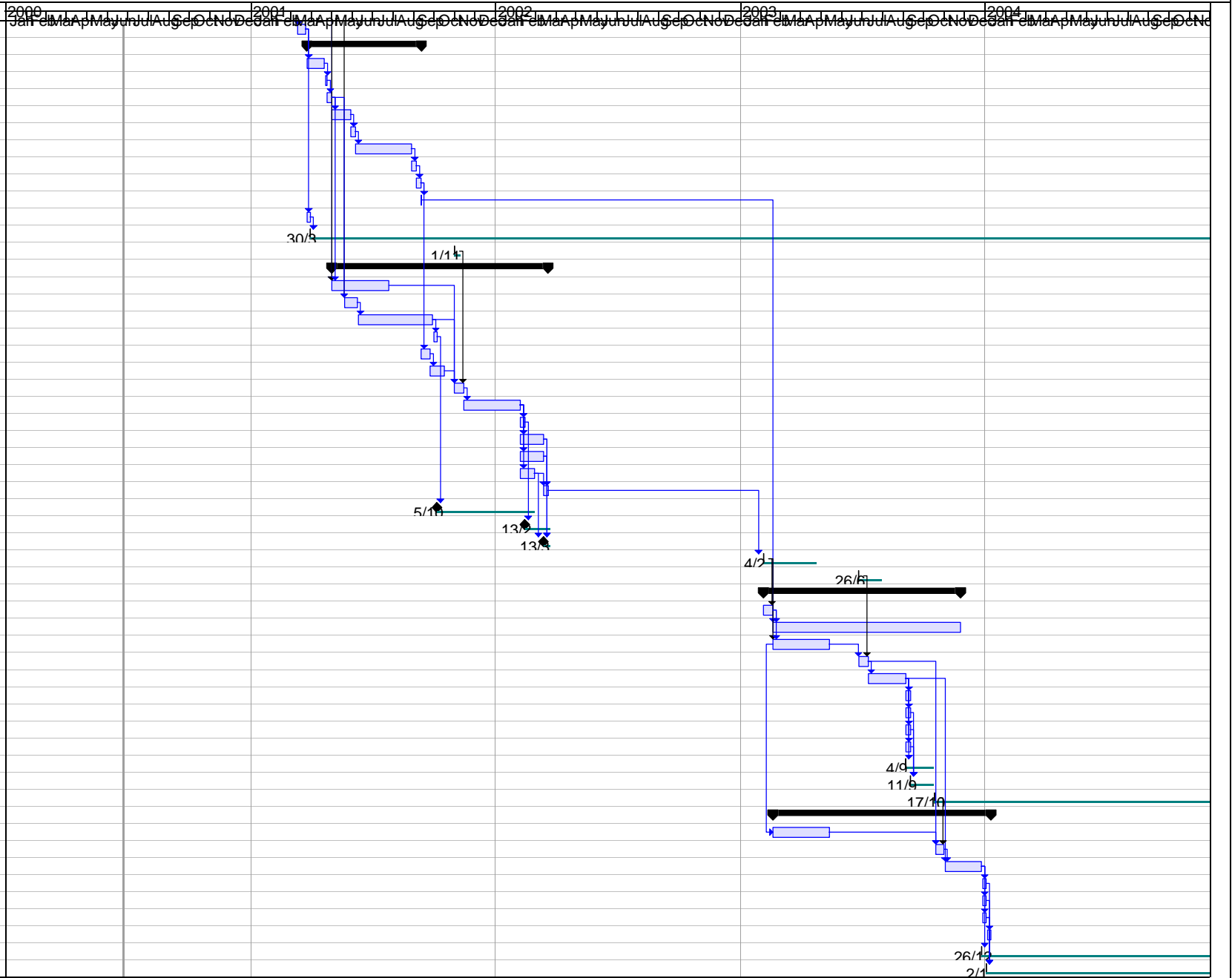


**Annex 3. SUBSYSTEM SCHEDULES**

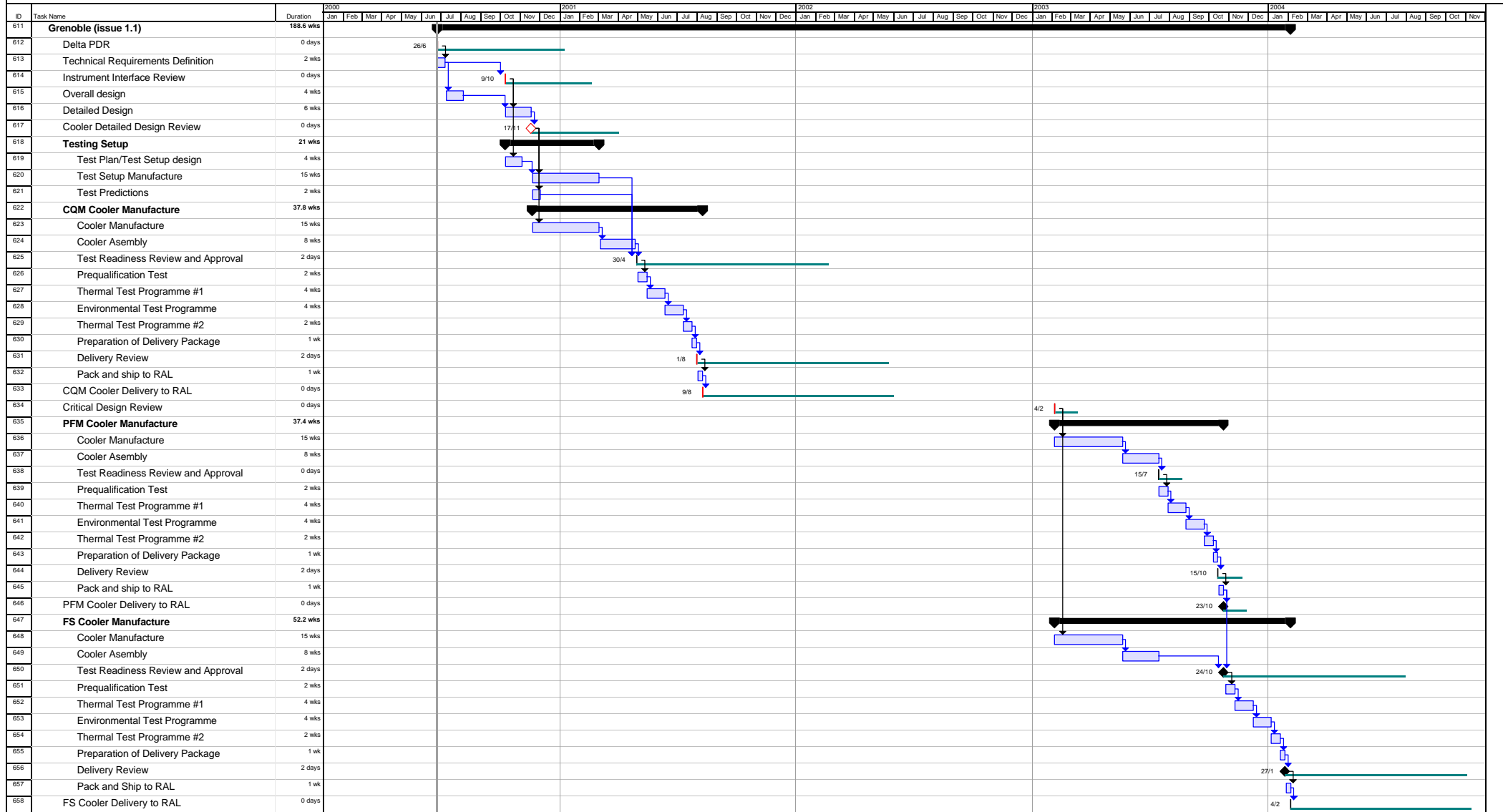


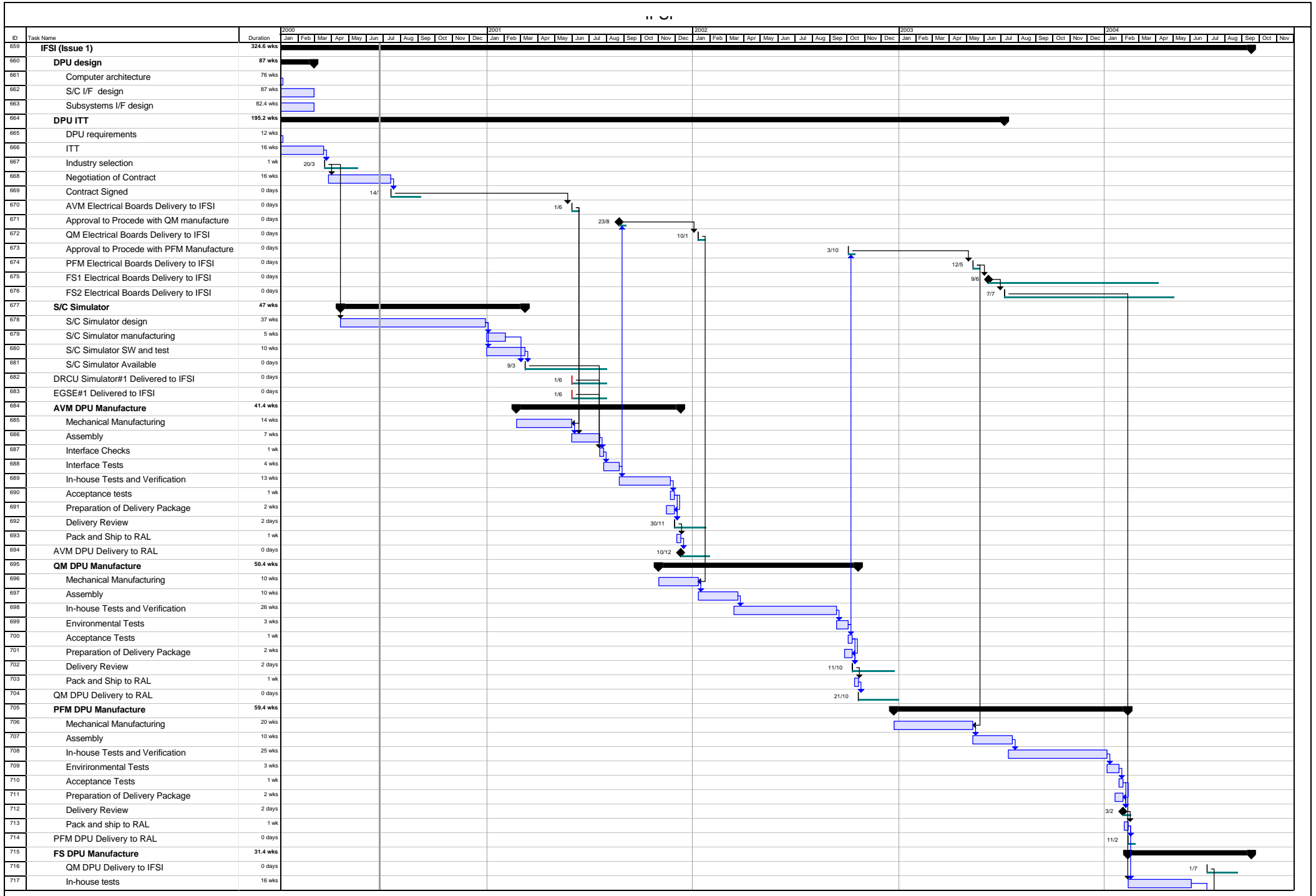




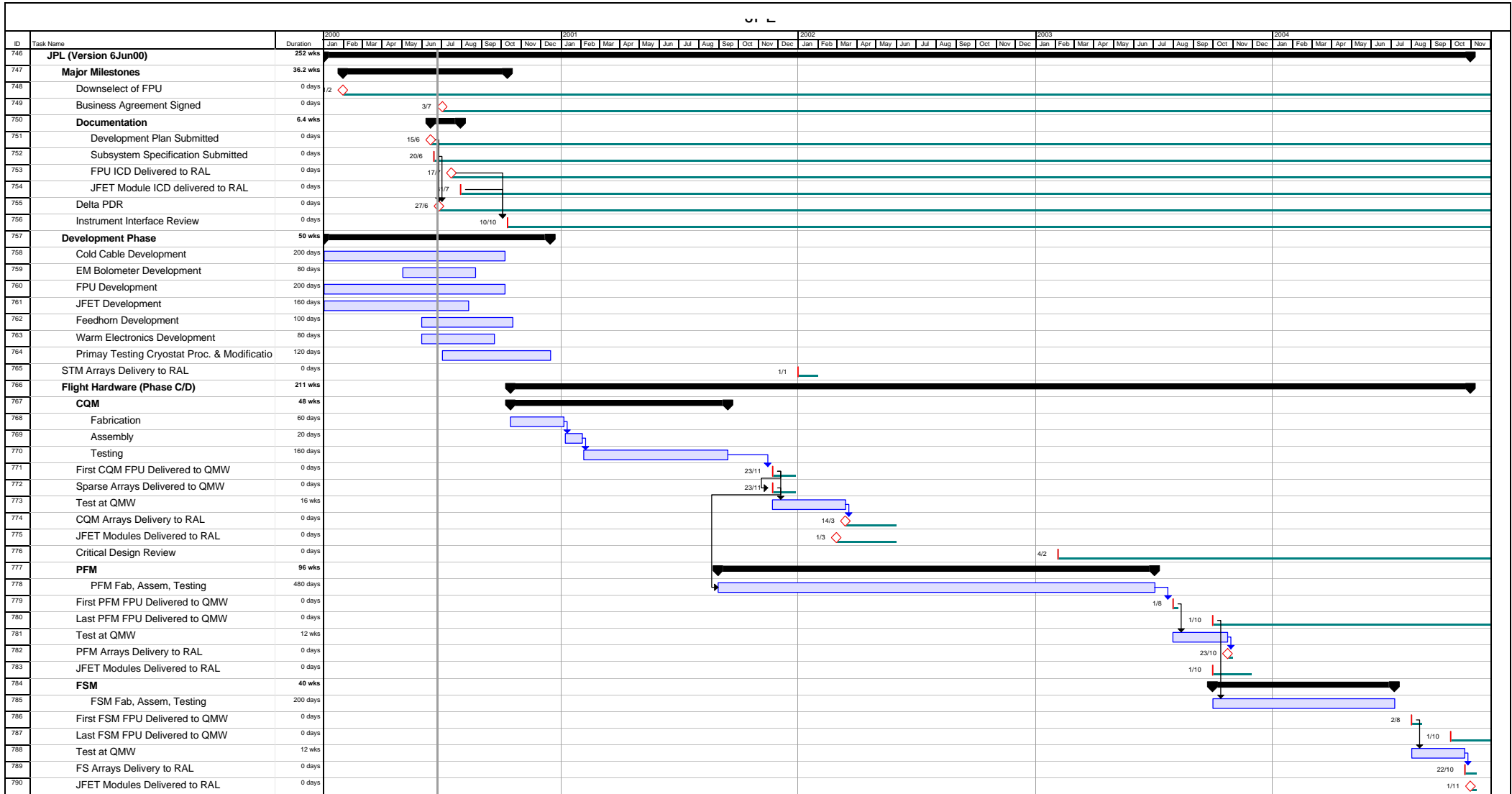


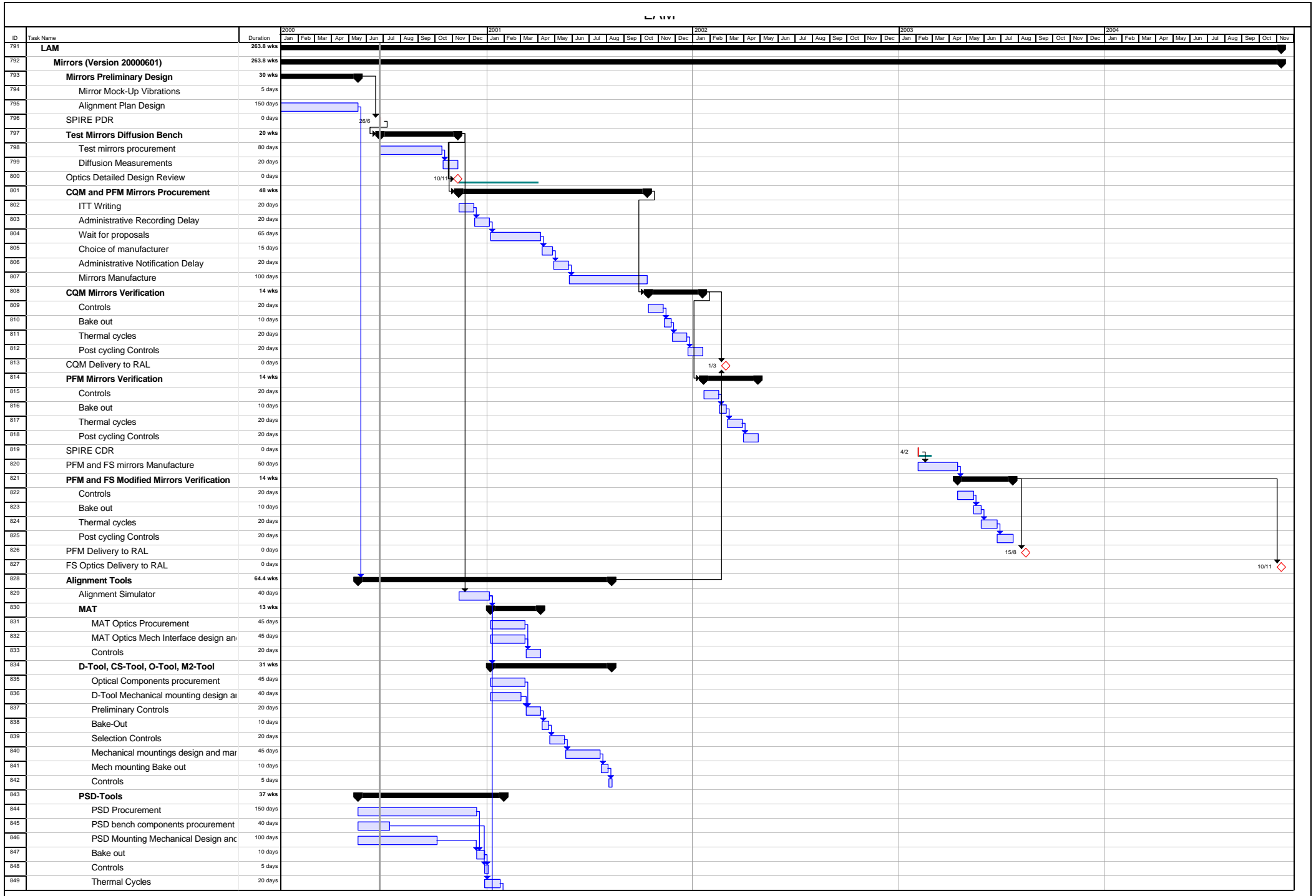
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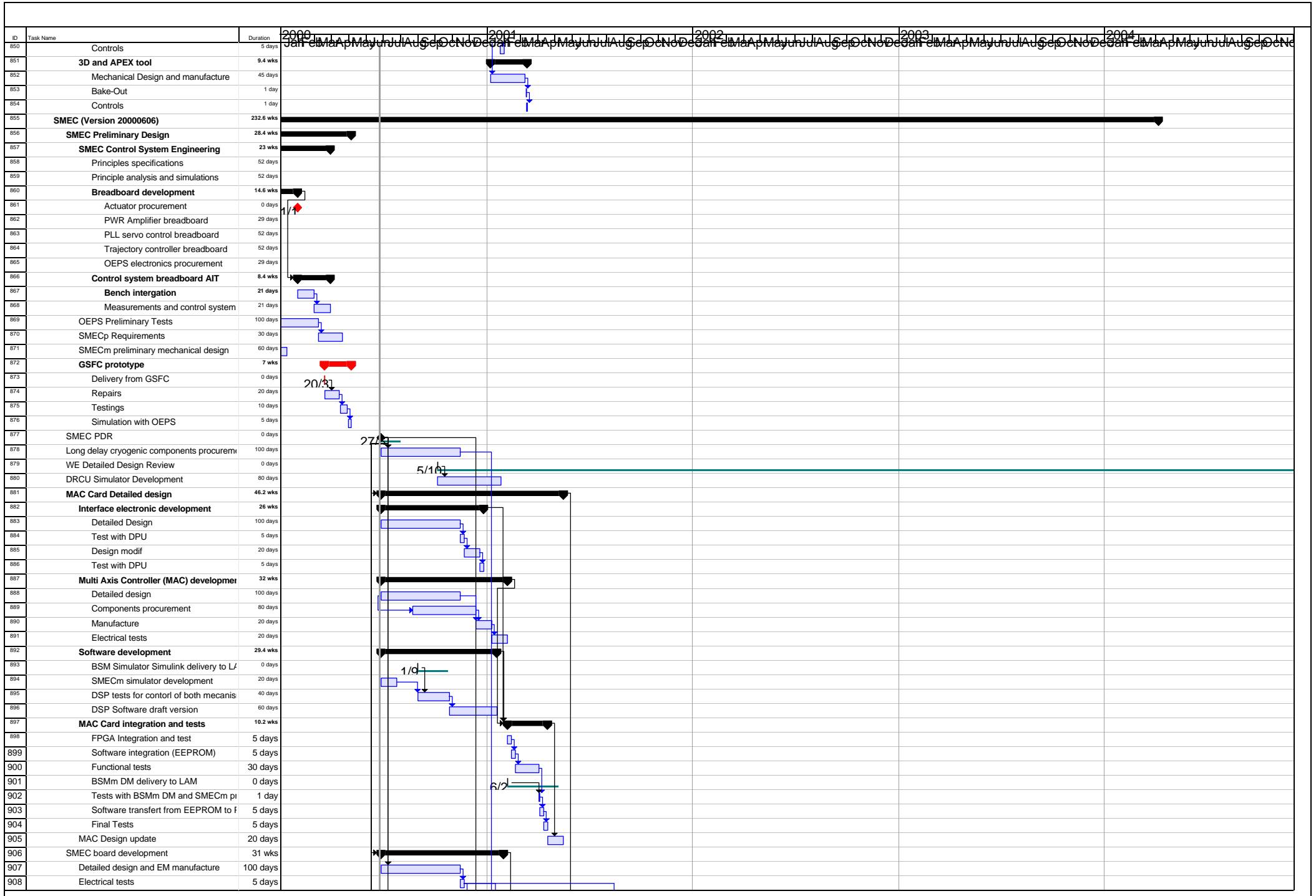


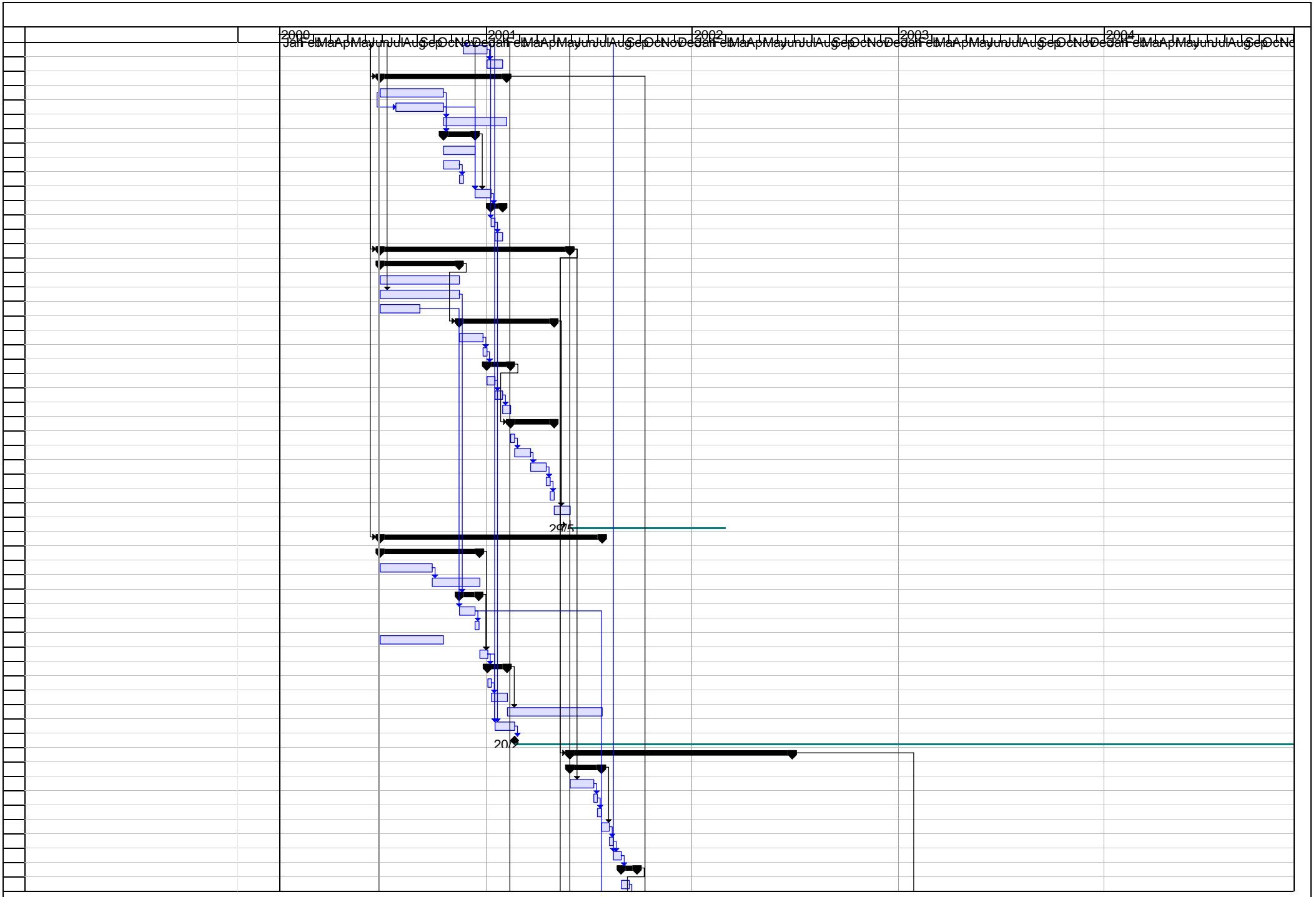




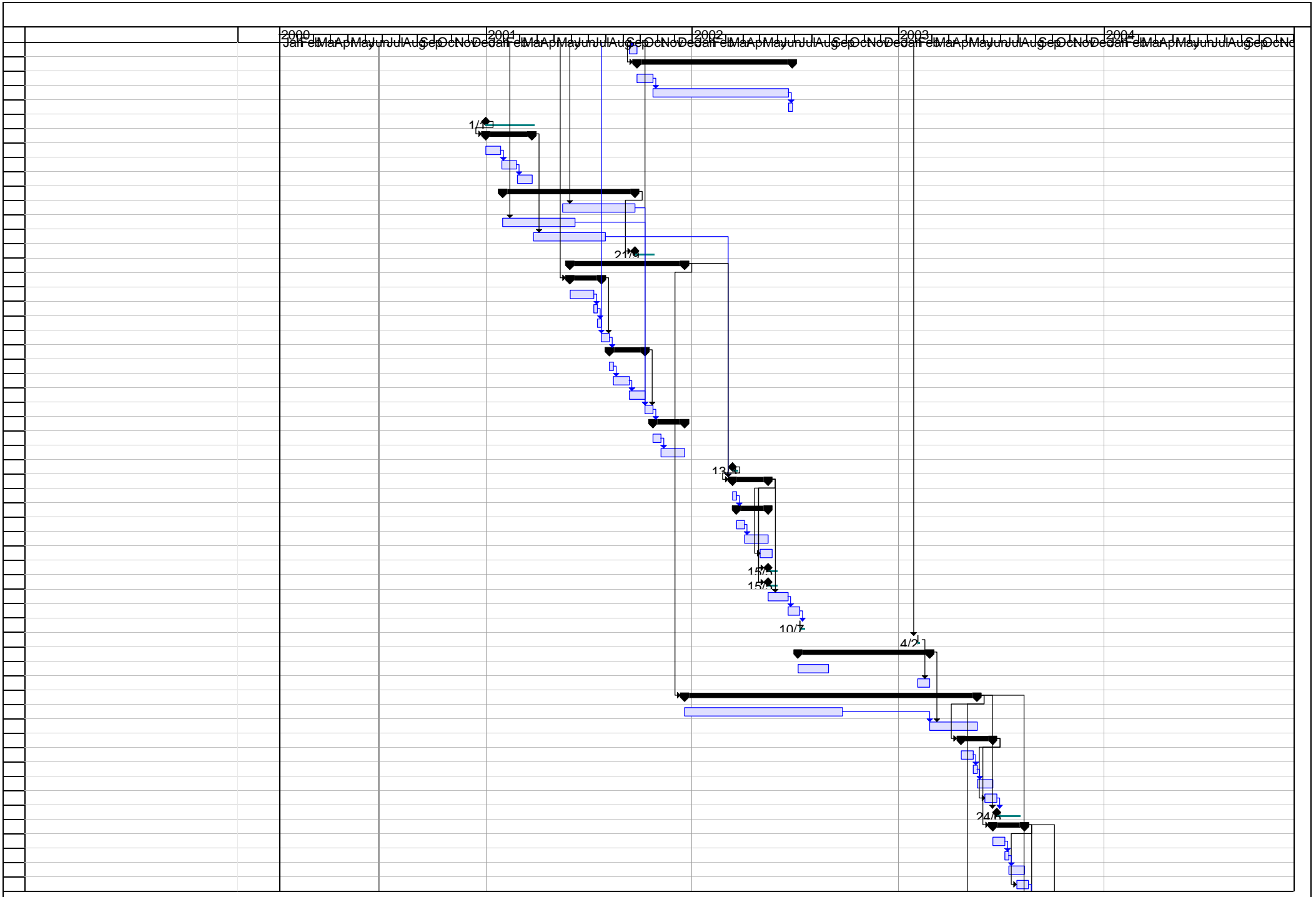


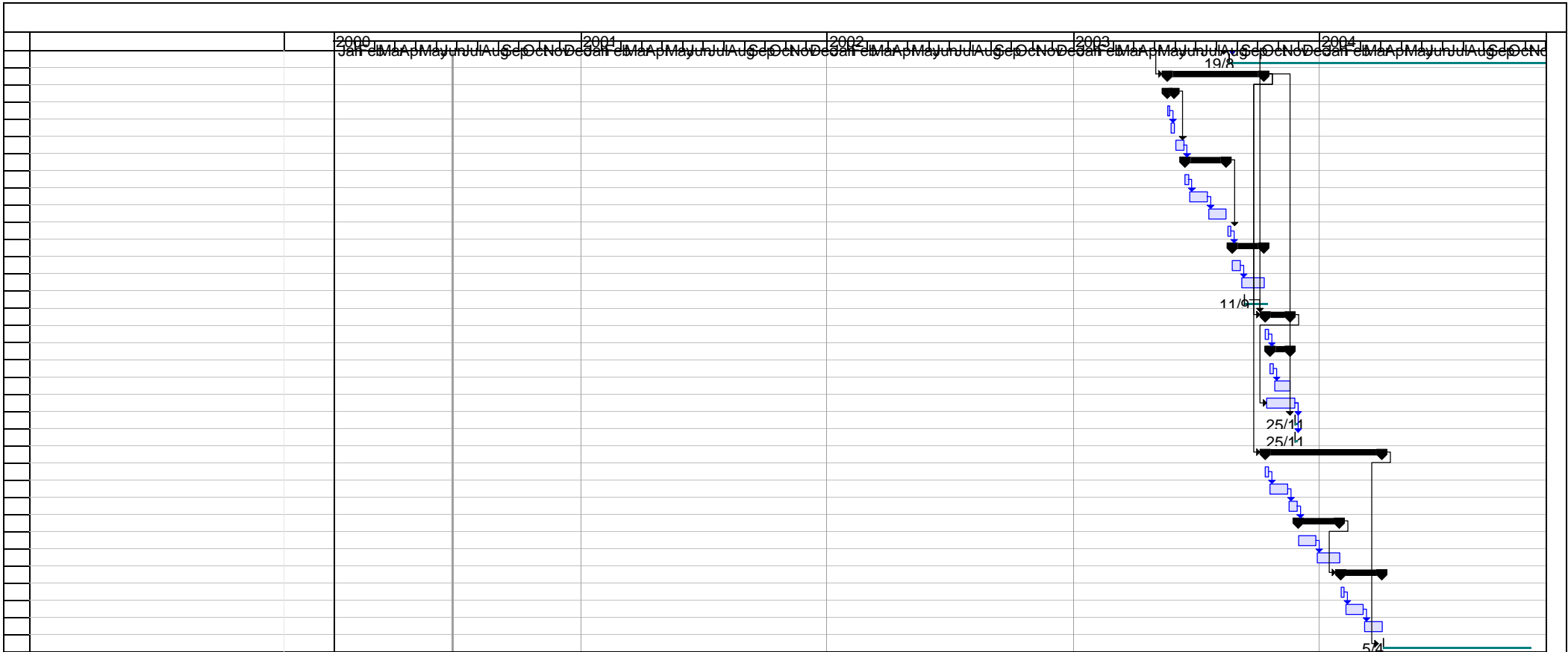




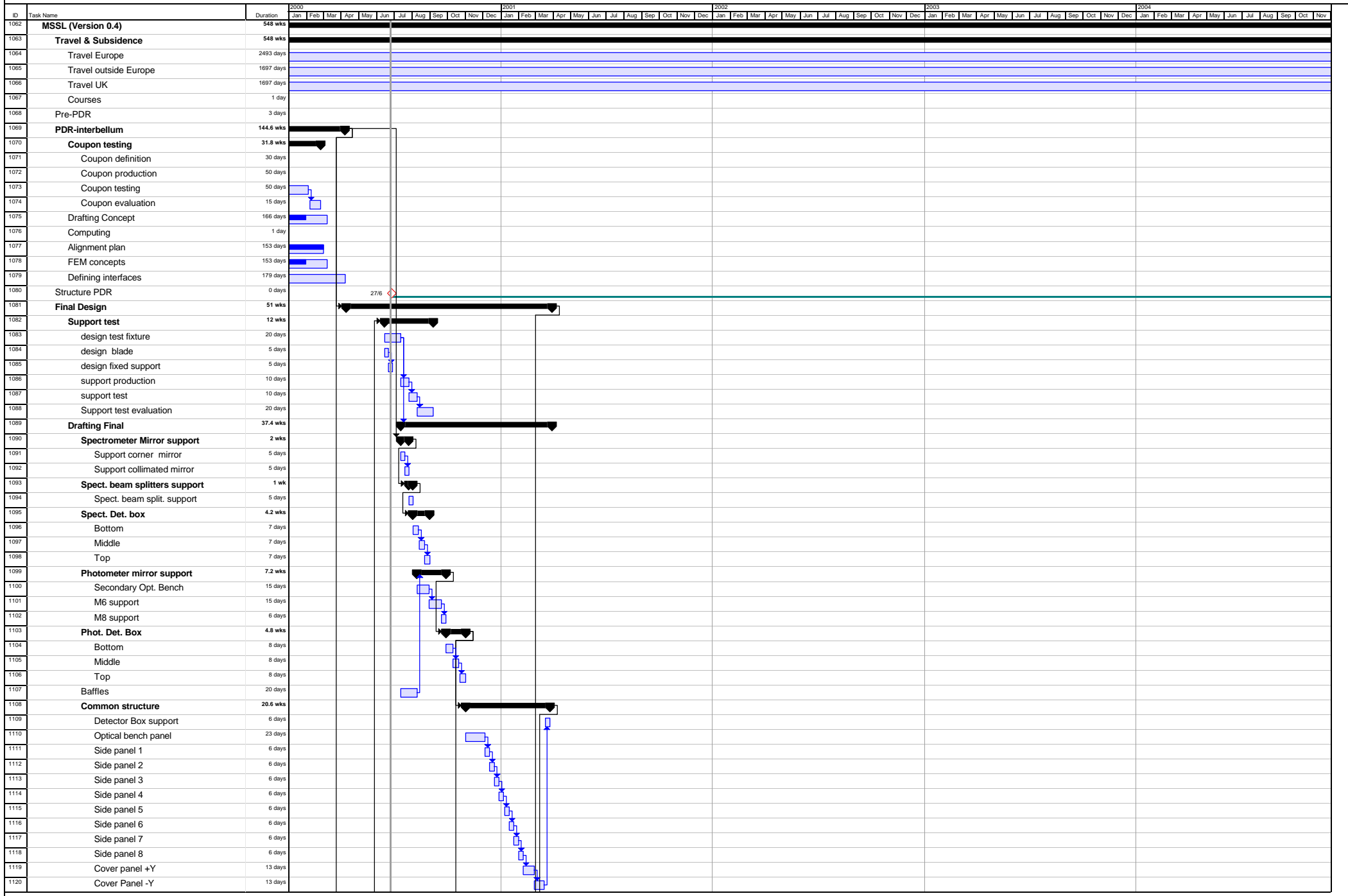


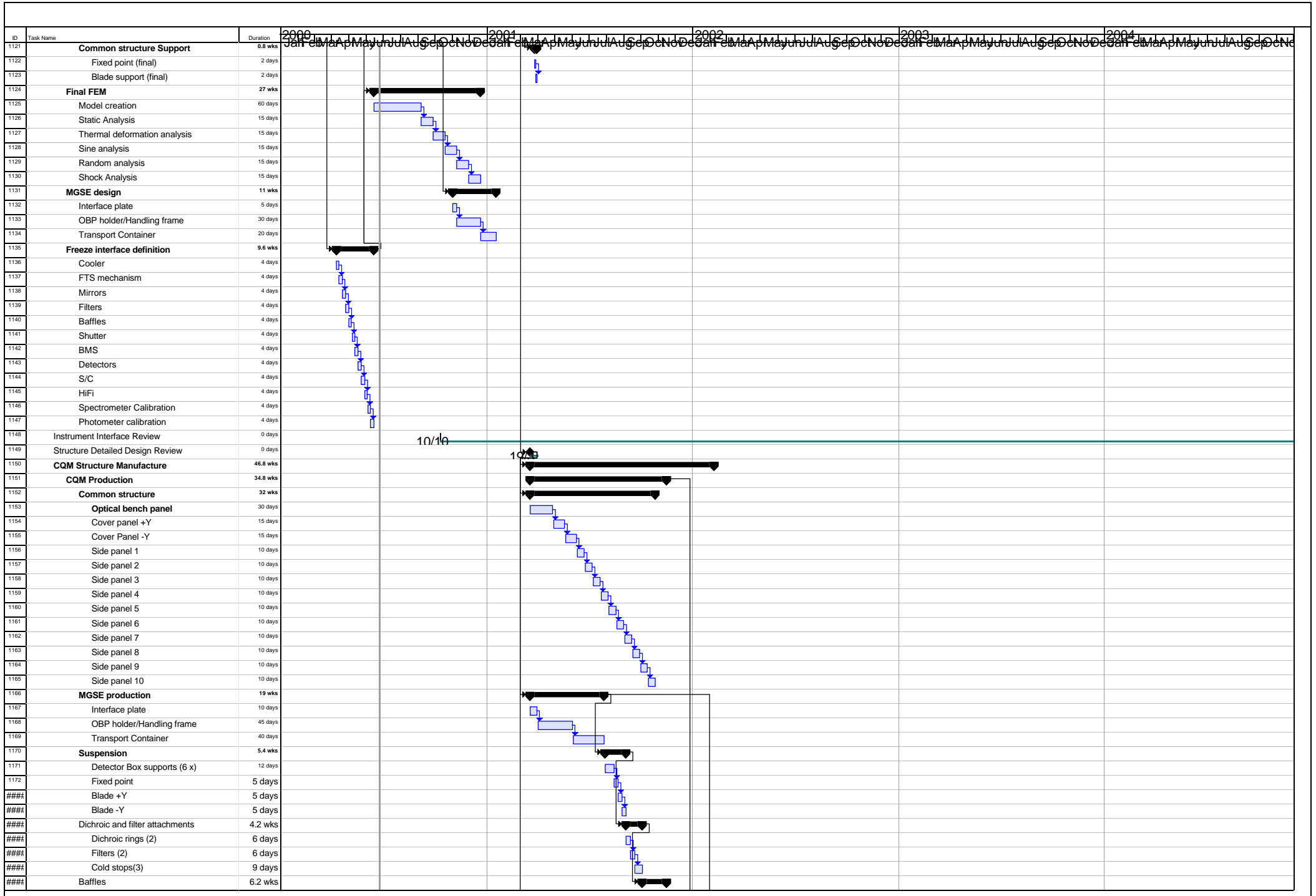


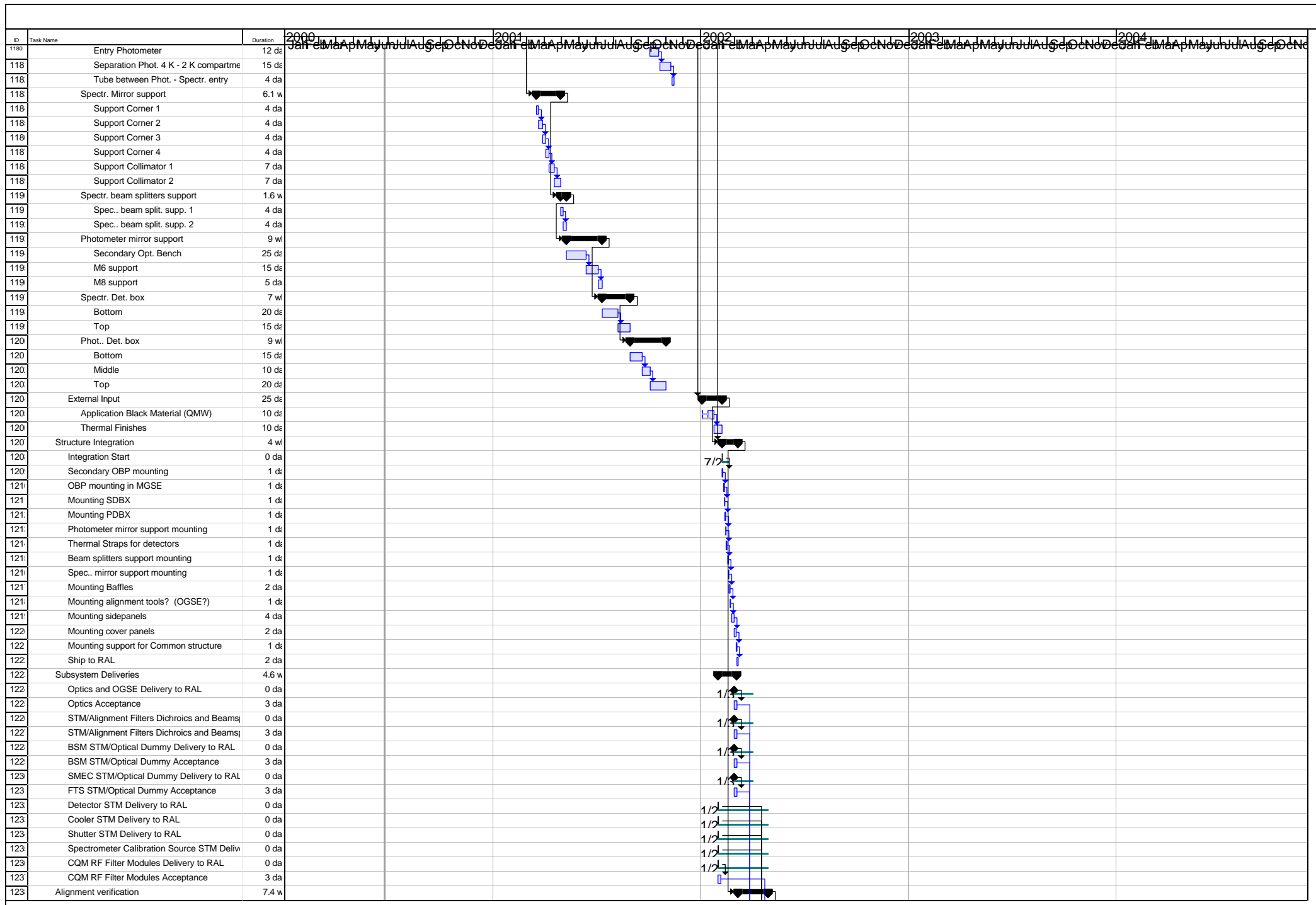


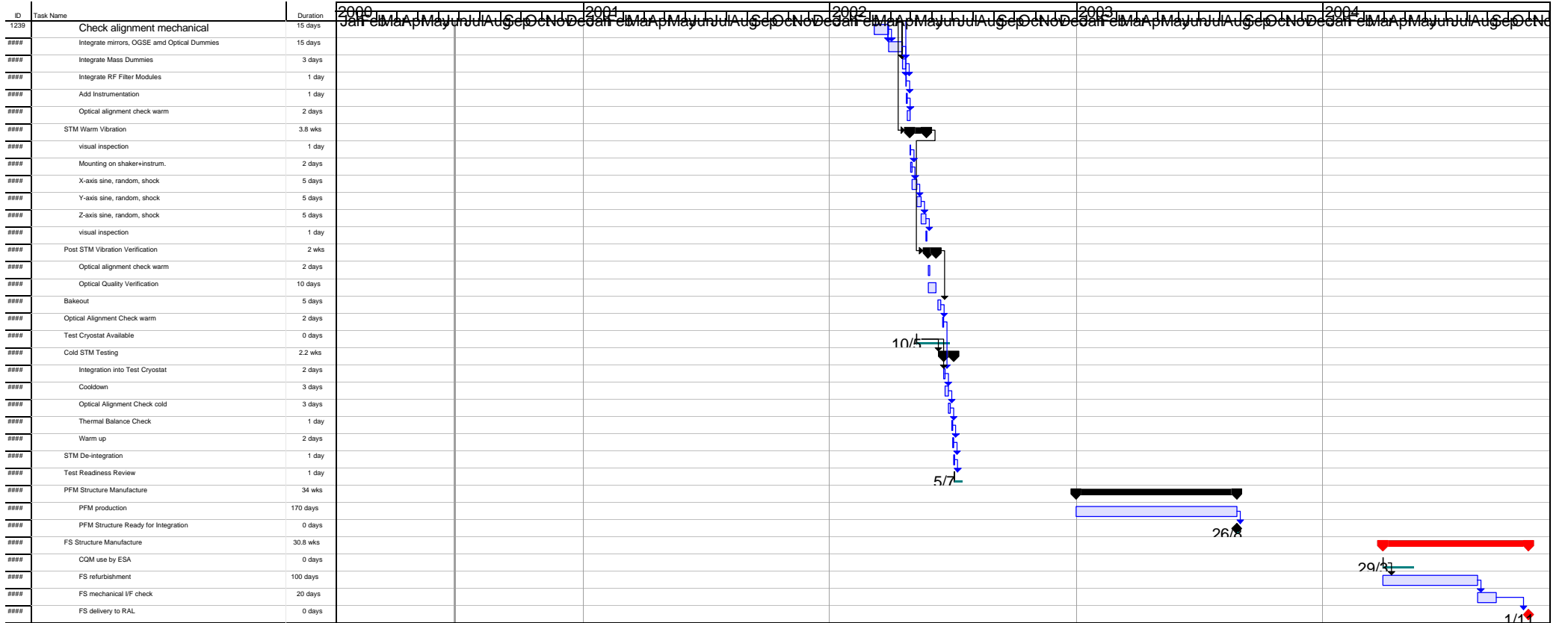


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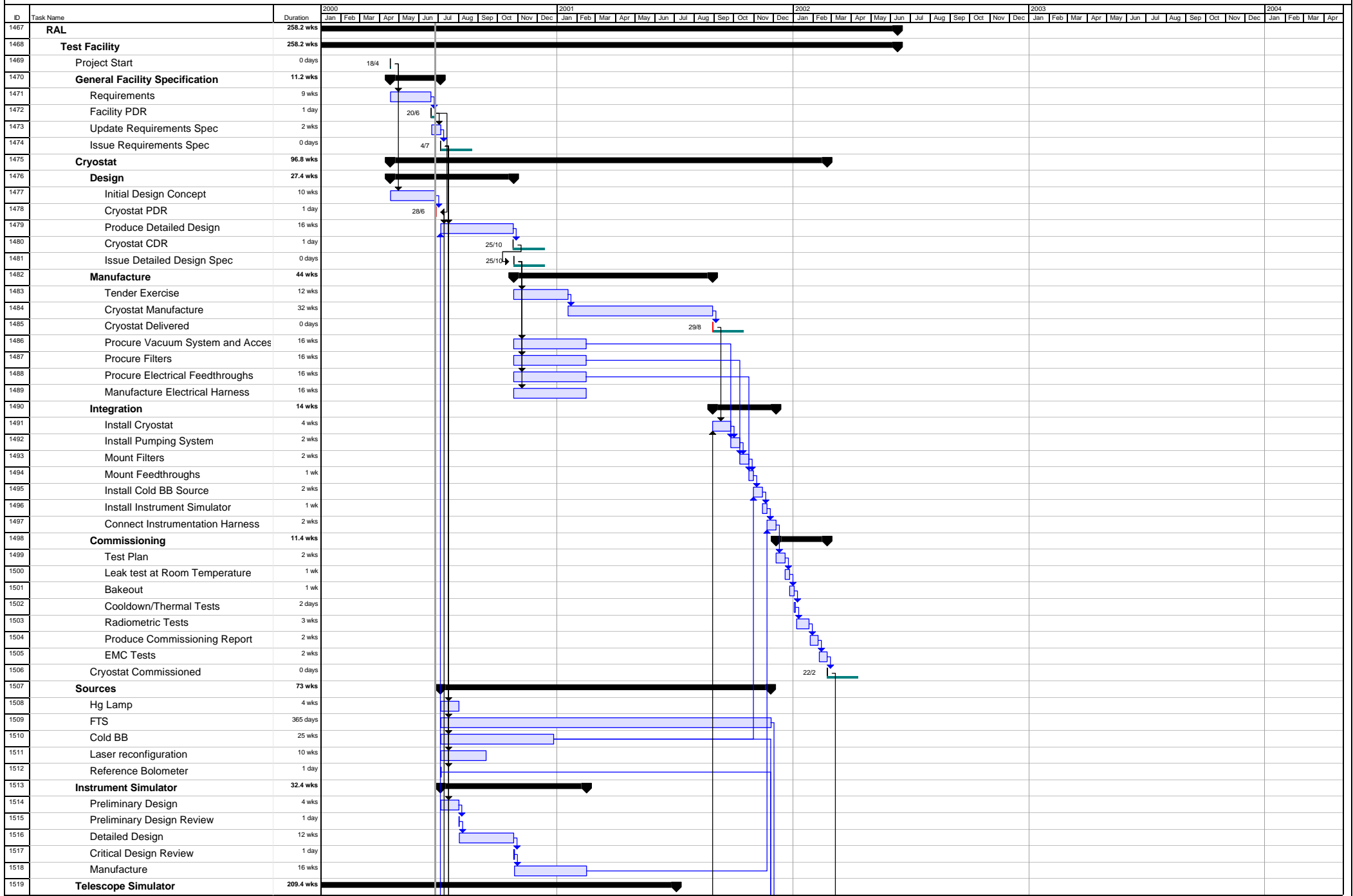




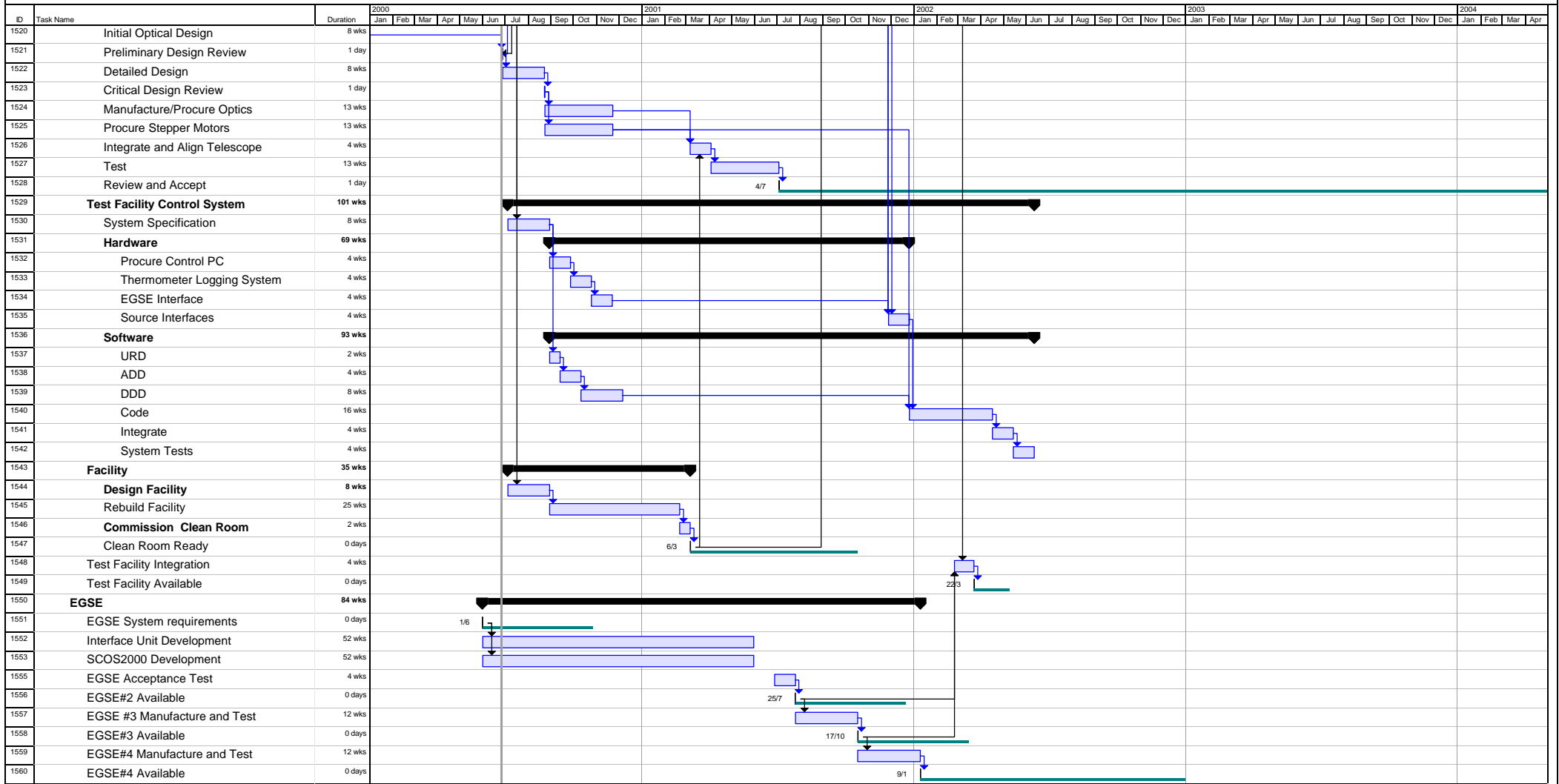




NPL



INFL





Saclay

